
“Evaluation of neutron resistivity of ECAL components”

2016/3/2

CALICE MTG @ Kyushu

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Outline

Expected Radiation

- ILC & ILD (ECAL) Structure
- Expected Radiation
- Radiation Damage and Requirement

Neutron irradiation Test

- Kobe Tandem
- CR39 sensor: Neutron Measurement
- Neutron Irradiation of ECAL parts

Evaluation

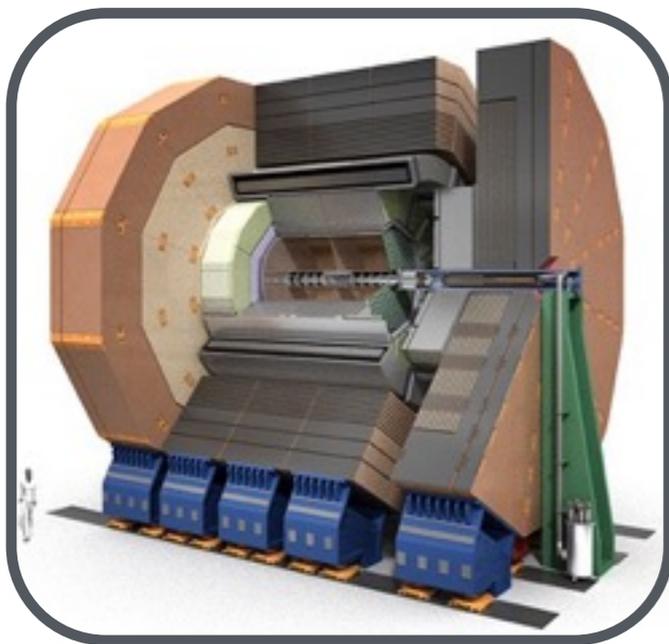
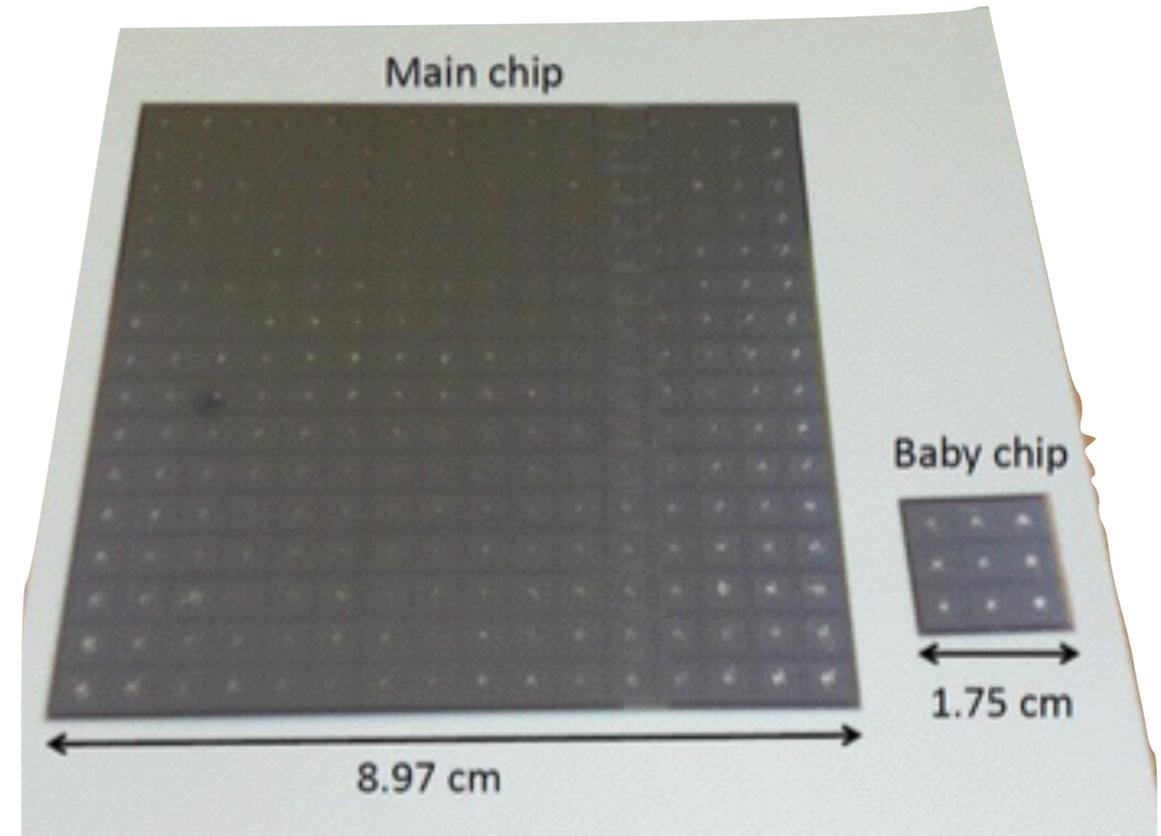
- Measurement of Radiation Damage
- Preliminary evaluation

ECAL parts [SiW]

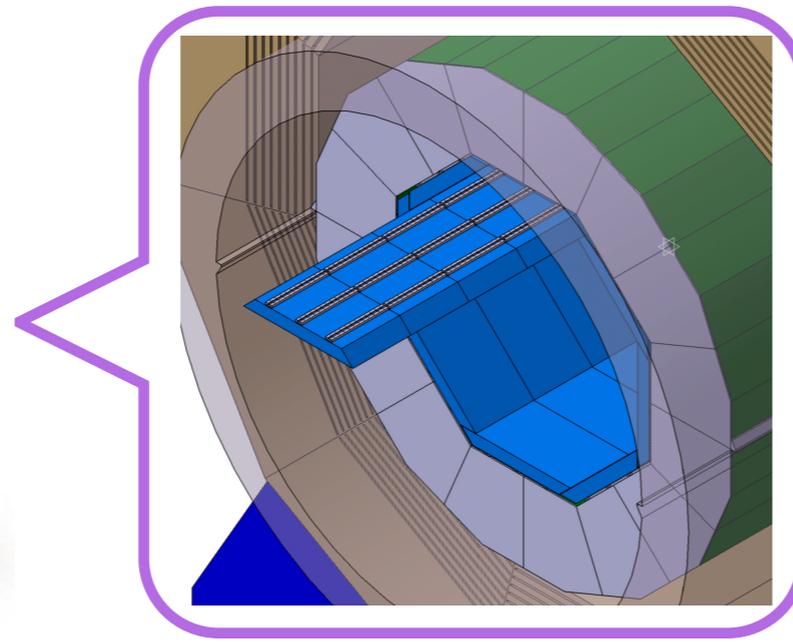
- 30 layers sandwiched calorimeter of Silicon PIN diode detector and W absorber

- Silicon PIN diode
 - ▶ 5×5 mm² pixel
 - ▶ 325 μm thickness
- W absorber

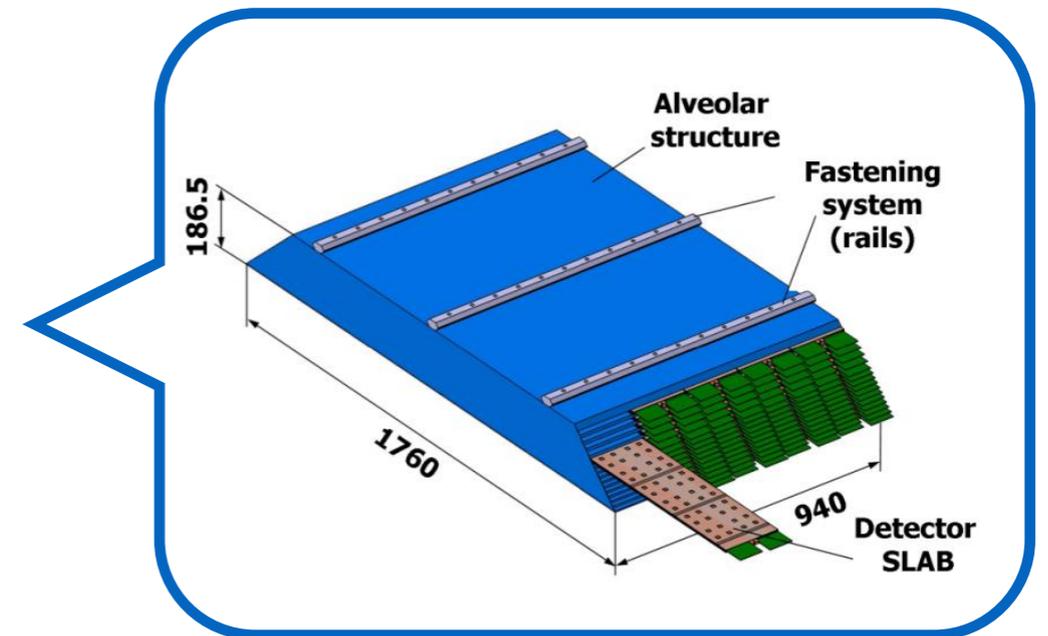
- ▶ Small Molière Radius ($R_M = 9\text{mm}$)
- ▶ Short Interaction Length ($X_0 = 3.5\text{mm}$)
- ▶ Large ratio of them ($\lambda/X_0 = 27.4$)



ILD



ECAL



Si PIN diode+ W Sandwich CAL

ECAL parts [super capacitor and glue]

super capacitor

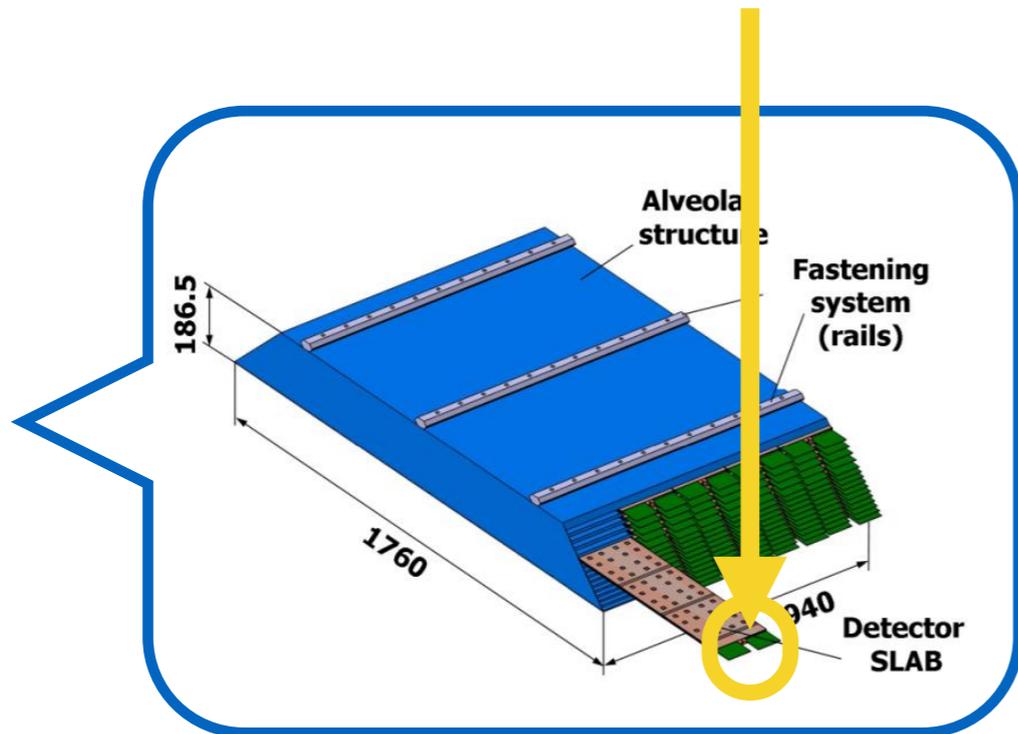


store power for power pulsing of readout circuit

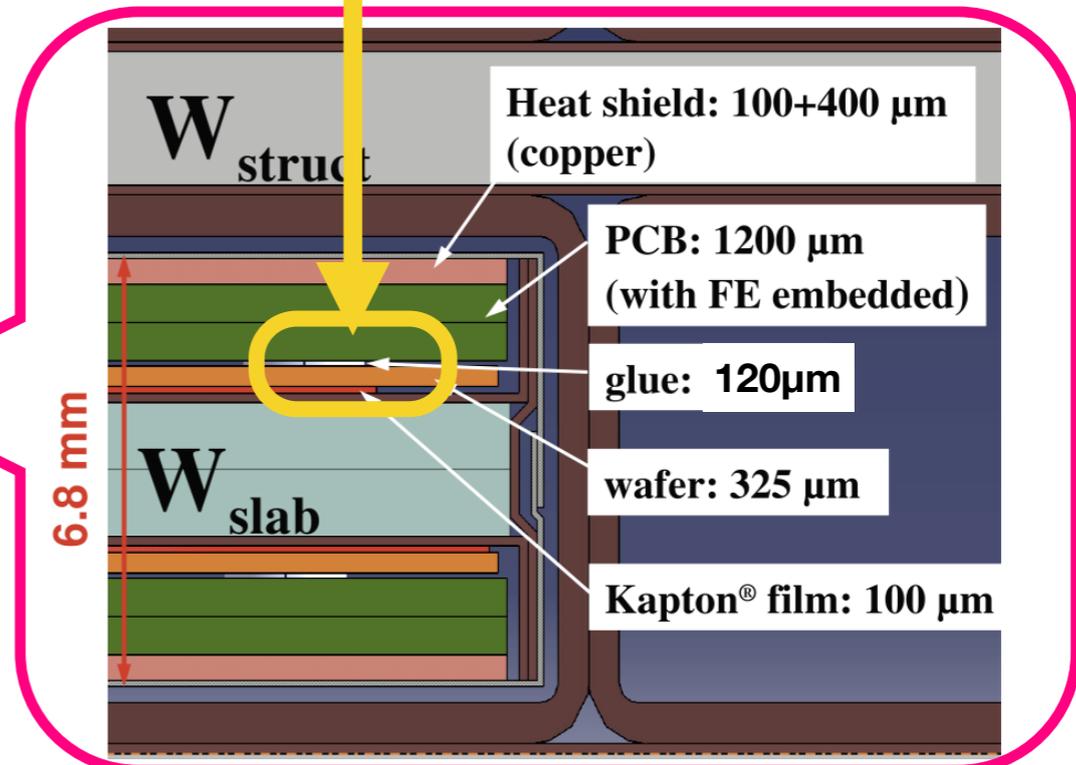
conductive glue



- adhere readout board and silicon
- Epoxy conductive glue

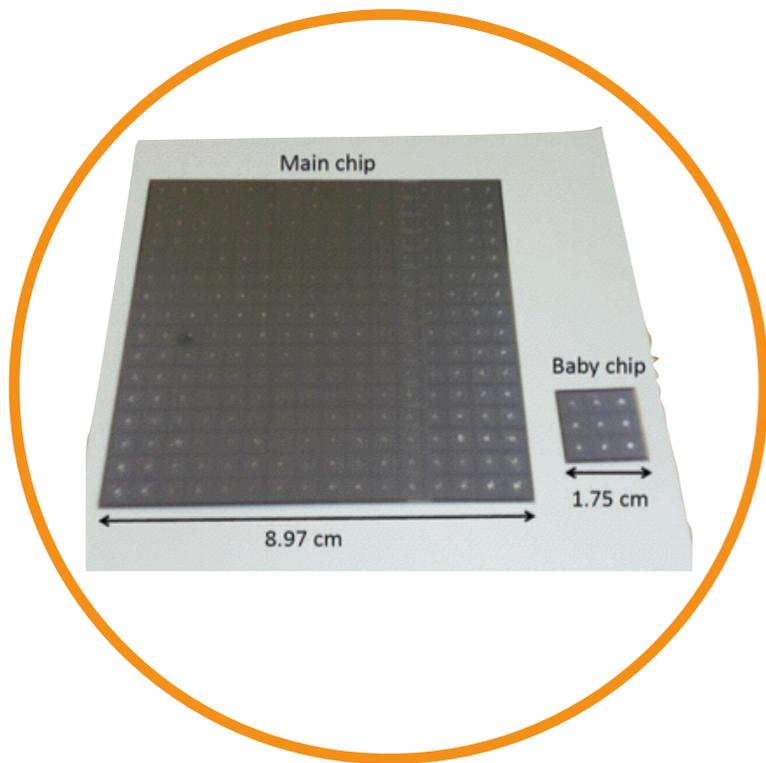


Si PIN diode + W Sandwich CAL

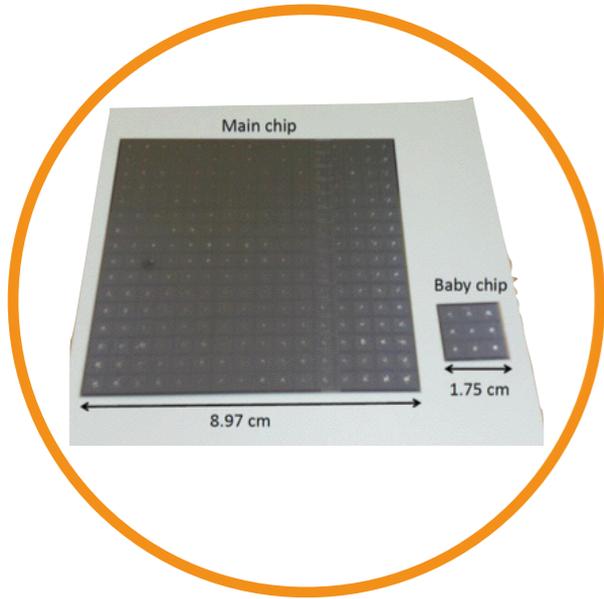


Research Purpose

- **Evaluation of neutron resistivity** of ECAL components: silicon, conductive glue, and super capacitor.
- Evaluation of lifetime and measurement accuracy, compared with the requirement of **ILD ECAL**.



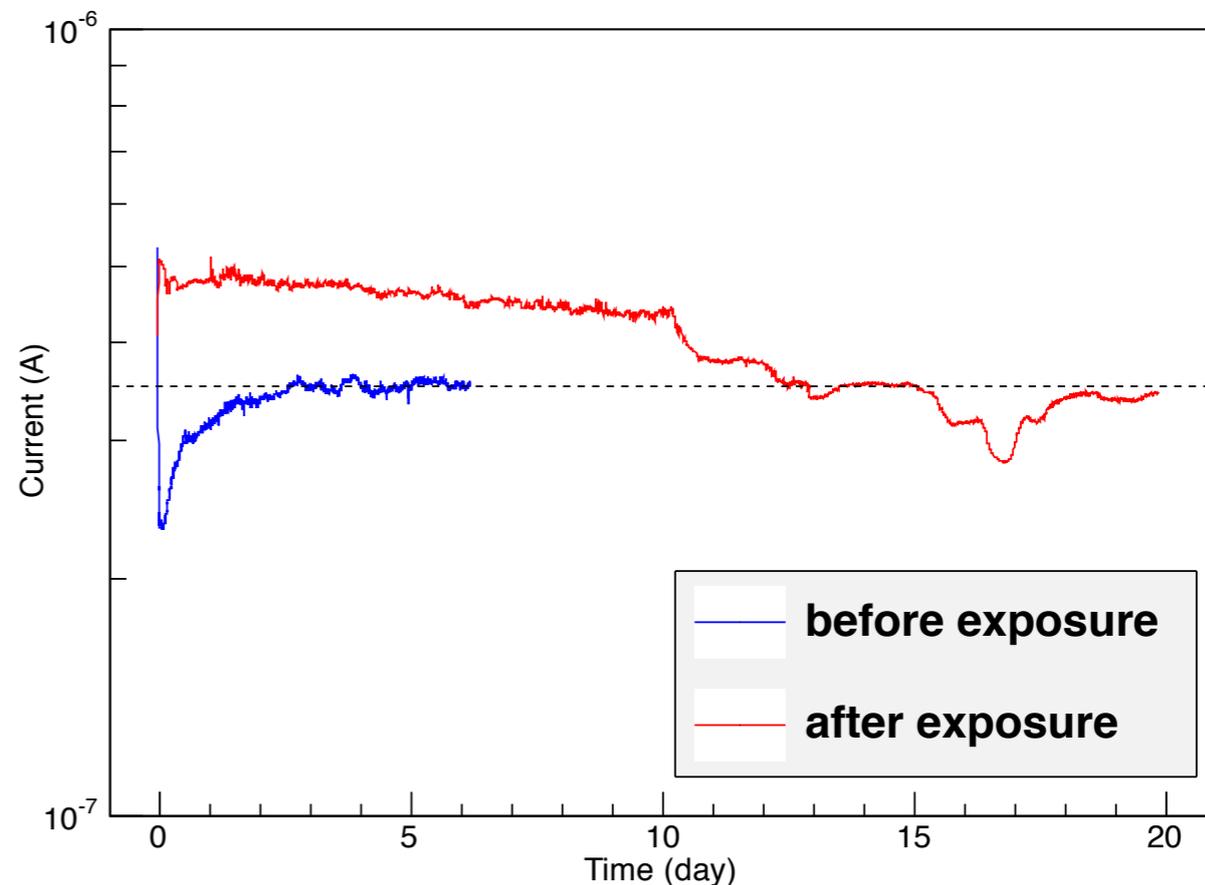
Radiation Damage in Silicon



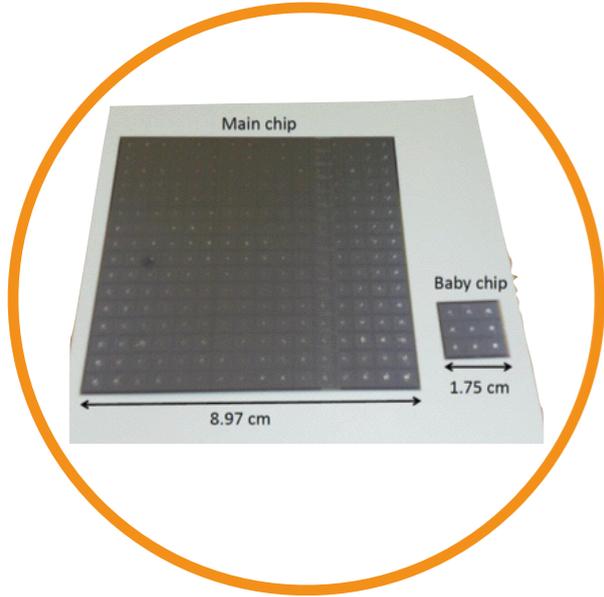
- **TID** (Total Ionising Dose Effect)
Electromagnetic interaction by large radiation dose including photons. Creating fixed charge and border energy level aggravate properties.
- **DDD** (Displacement Damage Dose Effect)
Particles create Frenkel defects in silicon crystal (**NIEL**) which degrade silicon properties.

Kyushu group researched and evaluated **TID** through **γ -ray irradiation of 100Gy (ILC: 1M year)**

Dark current of T323 (200V, 20deg)

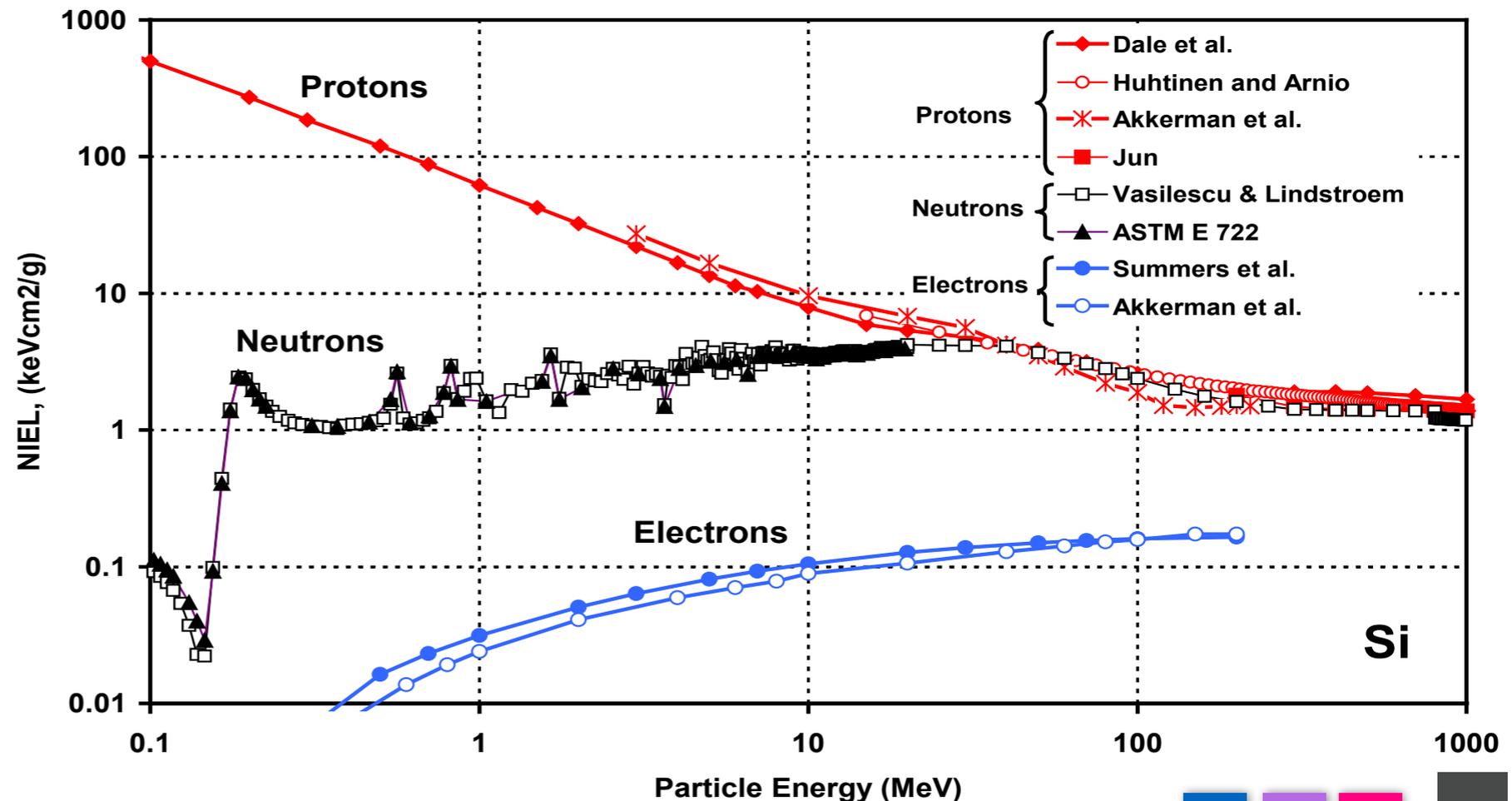
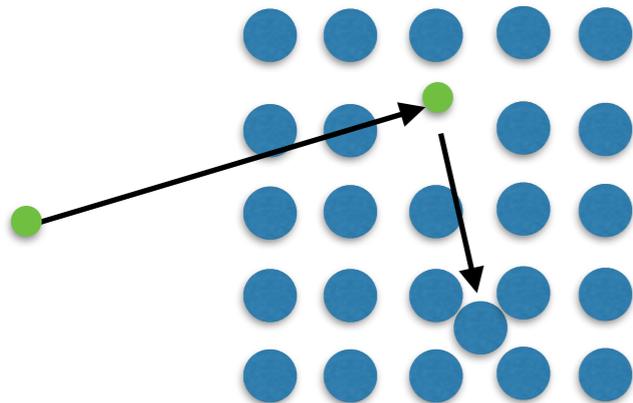


Radiation Damage in Silicon

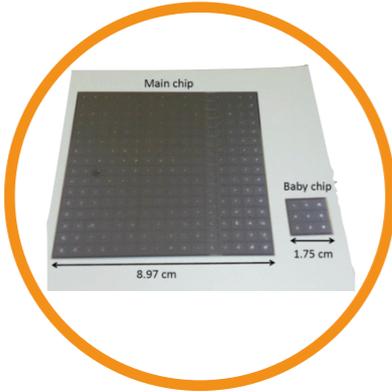


- **TID** (Total Ionising Dose Effect)
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NIEL Damage Function



Radiation Damage and ILC requirement



- increase of **dark current**
- change of **full depletion voltage**
- decrease of **collected charge**

- deterioration of **conductivity and adherence**

- change of **capacitance**

Required properties of ILD ECAL

1. **Dark current** is smaller than **SKIROC2 design limit 20 nA / channel**.
2. **Effective volume** does not change with **operating voltage**.
3. **Collected charge** is enough to detect **~ 0.2 MIPs**.
4. **continuity of conductivity and adherence**
5. **right action of electric circuit**

Expected Radiation

- Radiation Sources are classified as BDS and IP.

IP(Interaction Point)

△ Photon: beamstrahlung photons

× Photon: **RBS(Radiative Bhabha Scattering)**

× $e^- e^+$: **PC (Pair Creation)**

× hadrons: **γ - γ scattering (Minijets)**

BDS(beam delivery system)

- Photon: synchrotron radiation

- Neutron: γ -N scattering(beam pipe)

- Charged particle: Beam-Gas Interaction

- μ : Beam Halo Muons

- ? Neutron: Beam dumps

- ? others: Extraction Line Losses

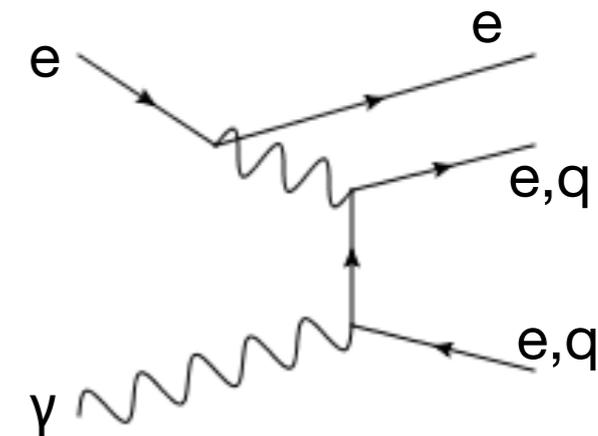
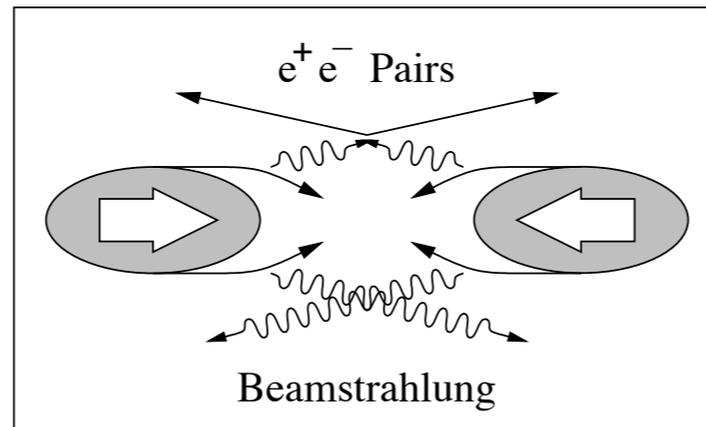
- can ignore radiation damage

- × **can't ignore radiation damage**

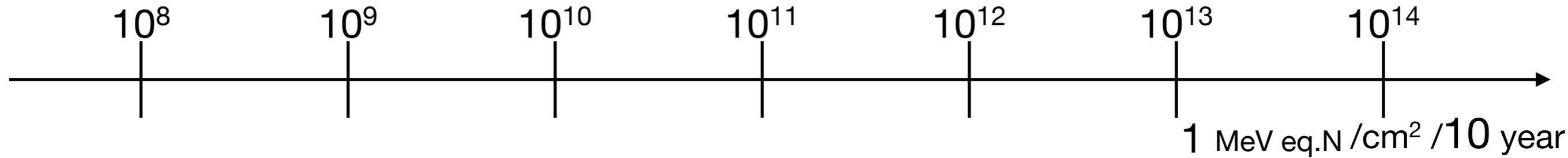
△ require appropriate evaluation

? require more detail

Spatial charge are attracted to each others by pinch effect and accelerated.



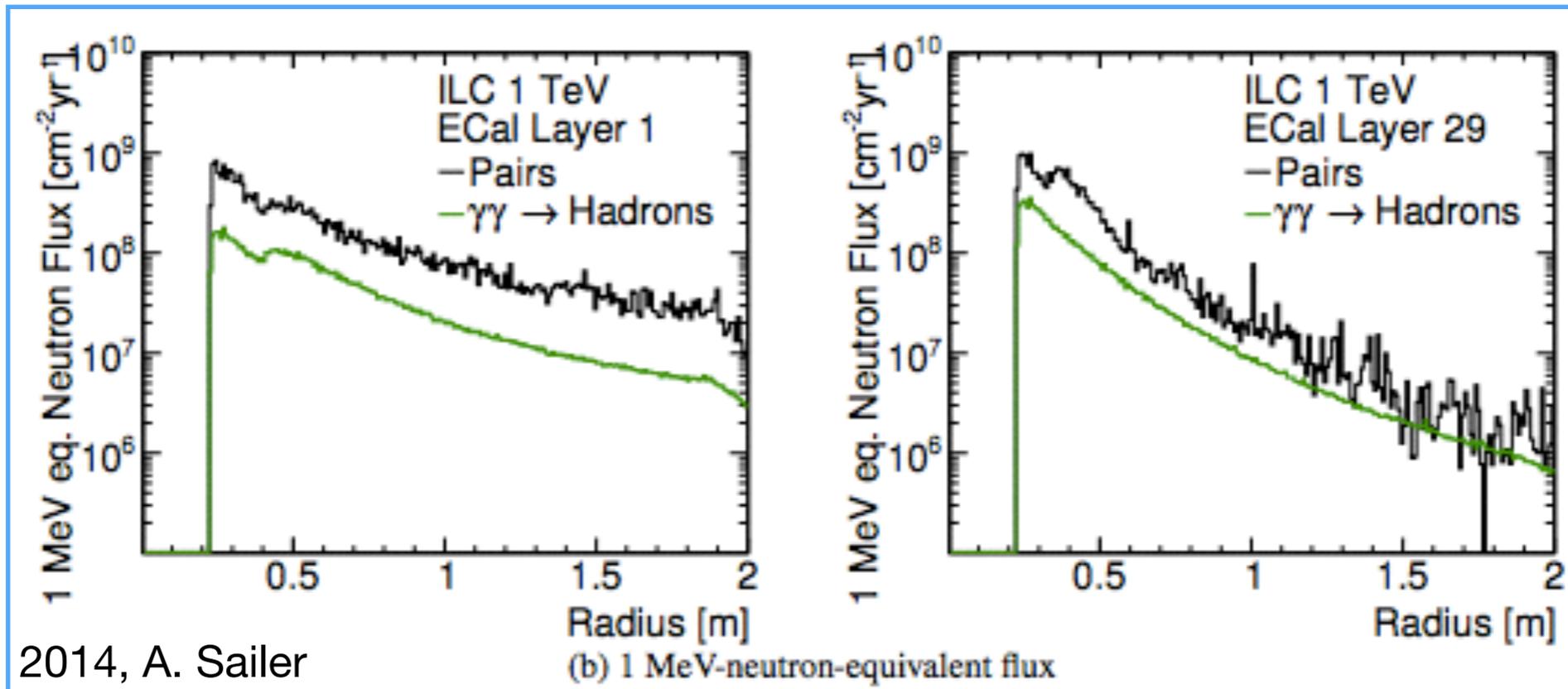
Expected Radiation



Beam Dump 2007, S. Darbha **ILC 500GeV VXD** $10^{10}-10^{11}$

pair+minijets 2014, A. Sailer **CLIC 3TeV ECAL** 10^9-10^{11}

pair+minijets 2014, A. Sailer **ILC 1TeV ECAL** 10^7-10^{10}



Neutron irradiation test was conducted by about 10^{10-11} n_{eq}/cm²

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Neutron irradiation Test

- Kobe Tandem
- CR39: Neutron Measurement
- Neutron Irradiation of ECAL parts

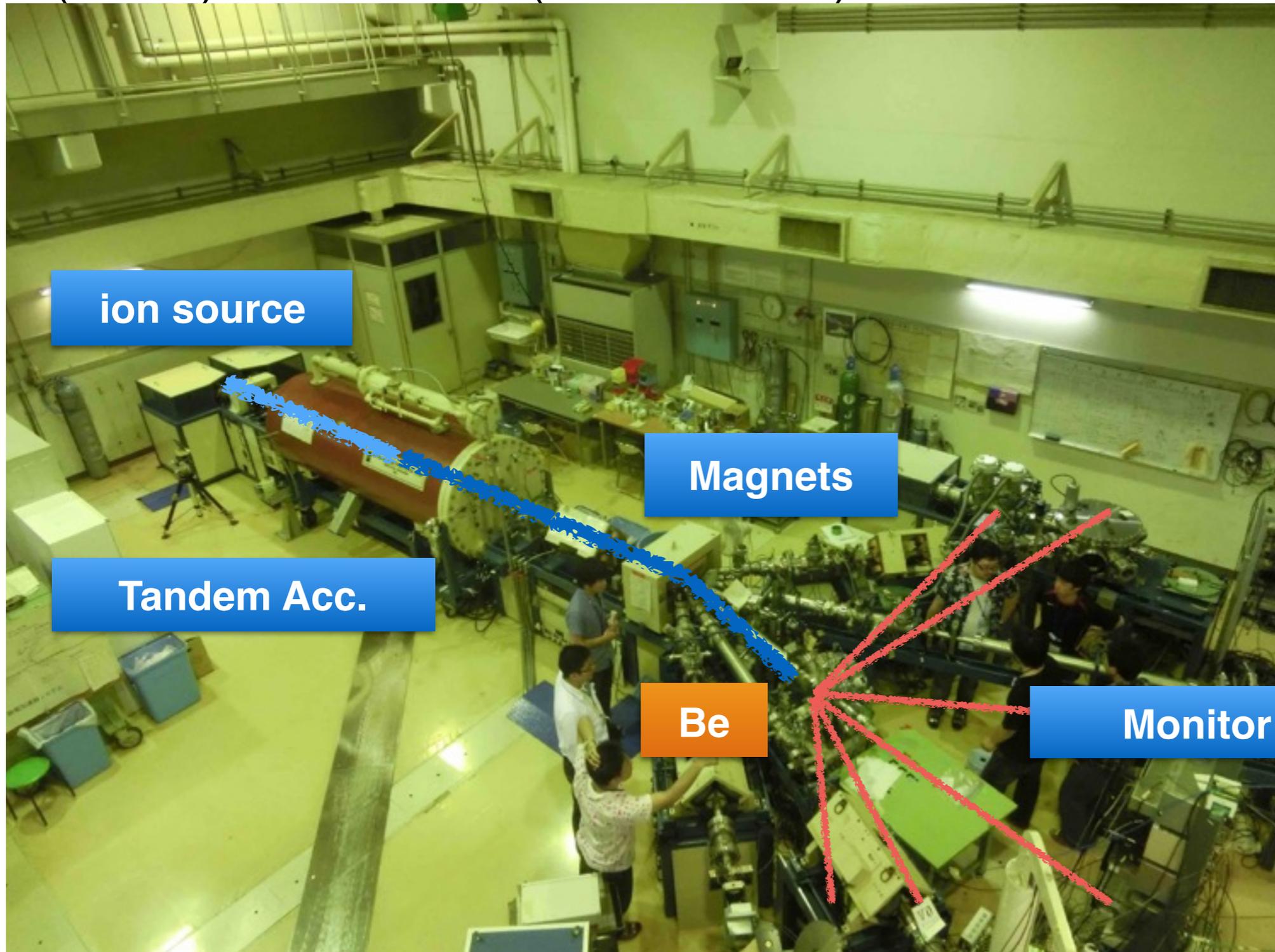
Evaluation

- Measurement of Radiation Damage
- Evaluation

Neutron Irradiation Test

- Kobe tandem accelerator
 $d(3 \text{ MeV}) + \text{Be} \rightarrow \text{B} + n$ ($Q = 4.36 \text{ MeV}$)

Thanks to Mr. Ochi(Kobe)
and Mr. Ueno(KEK)

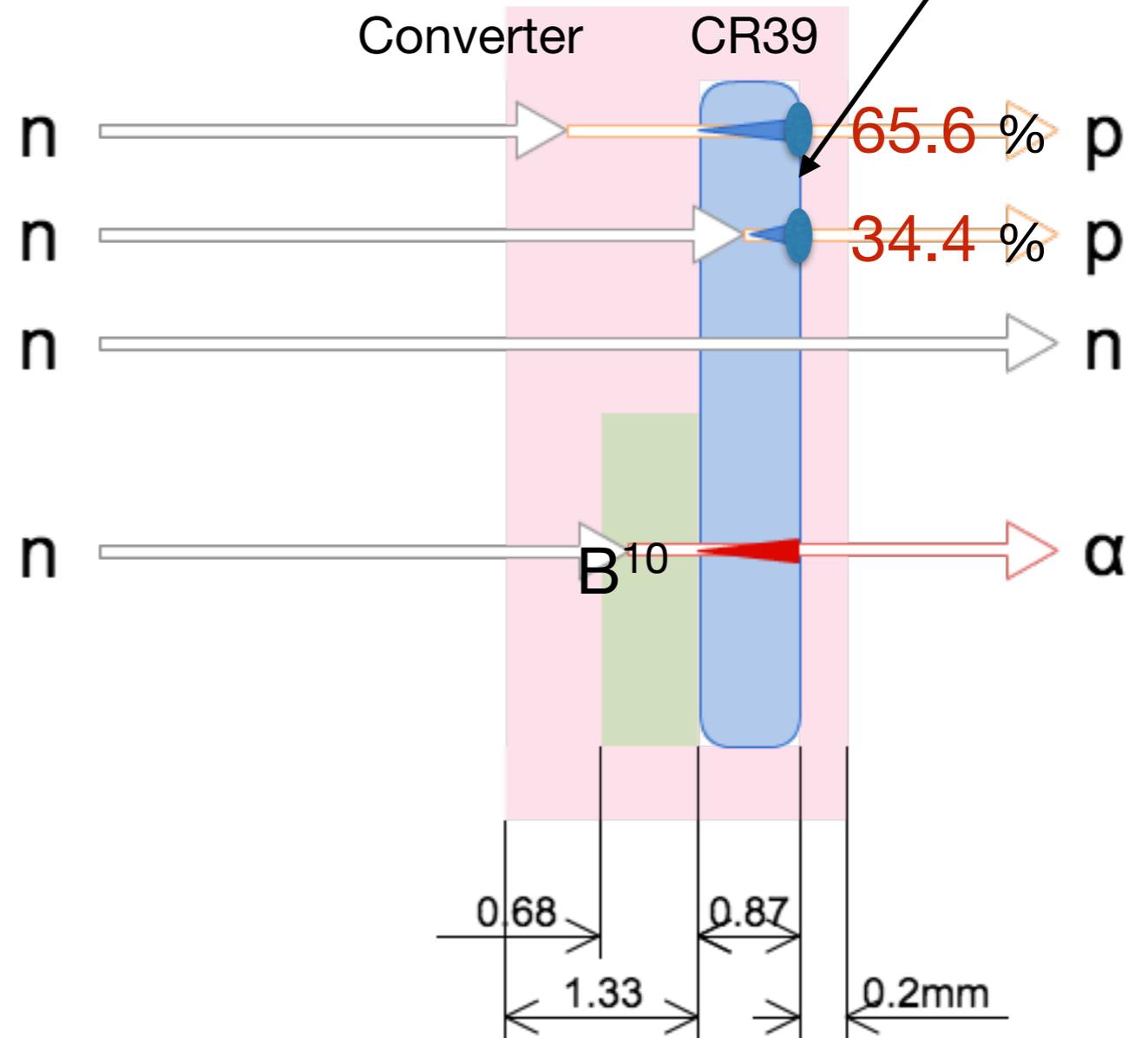


$E_{n,max} =$
7.36 MeV

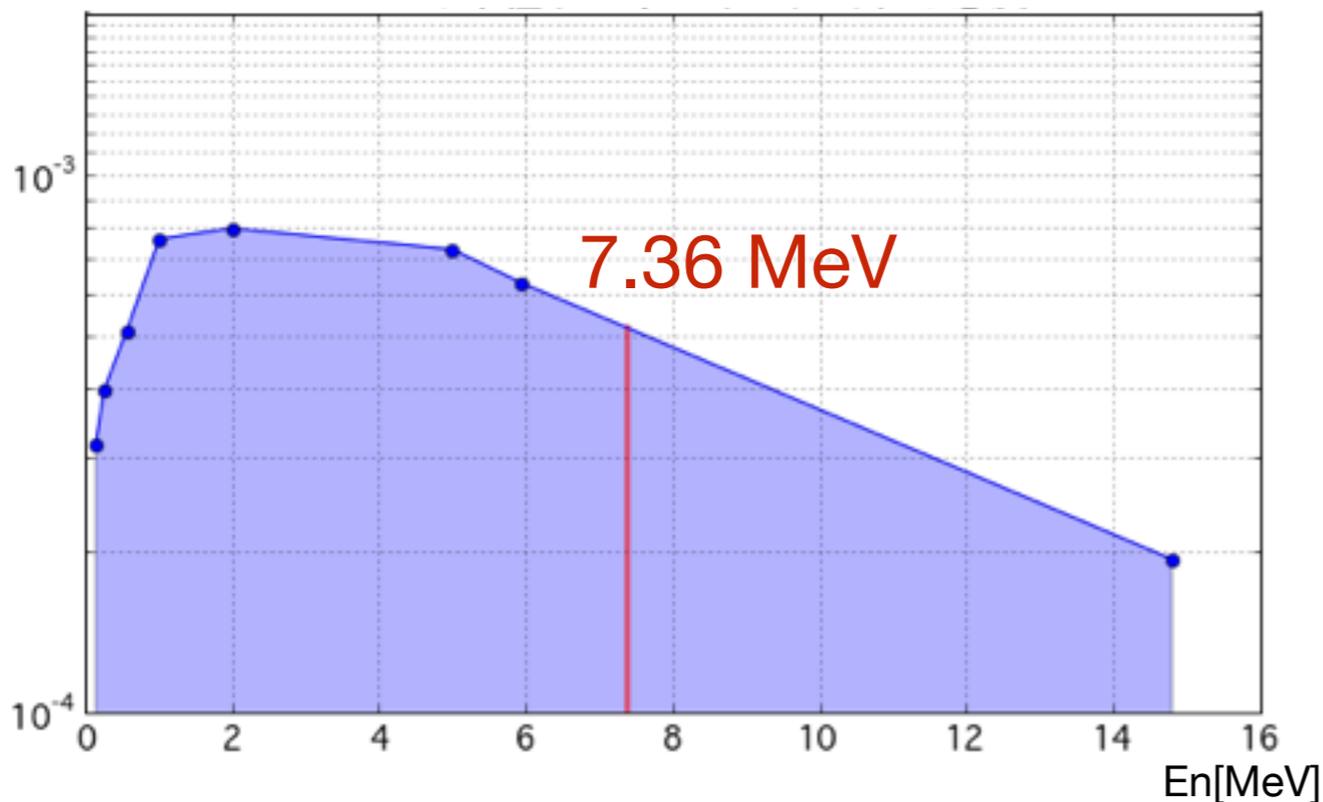
Neutron measurement by CR39 sensor

We counts # of pits on this surface.

- Neutrons converted to protons, which damage CR39.
- The probability of detecting fast neutron is 10^{-4} .
- We know CR39 sensor's energy sensitivity in range 0.145~14.8 MeV.



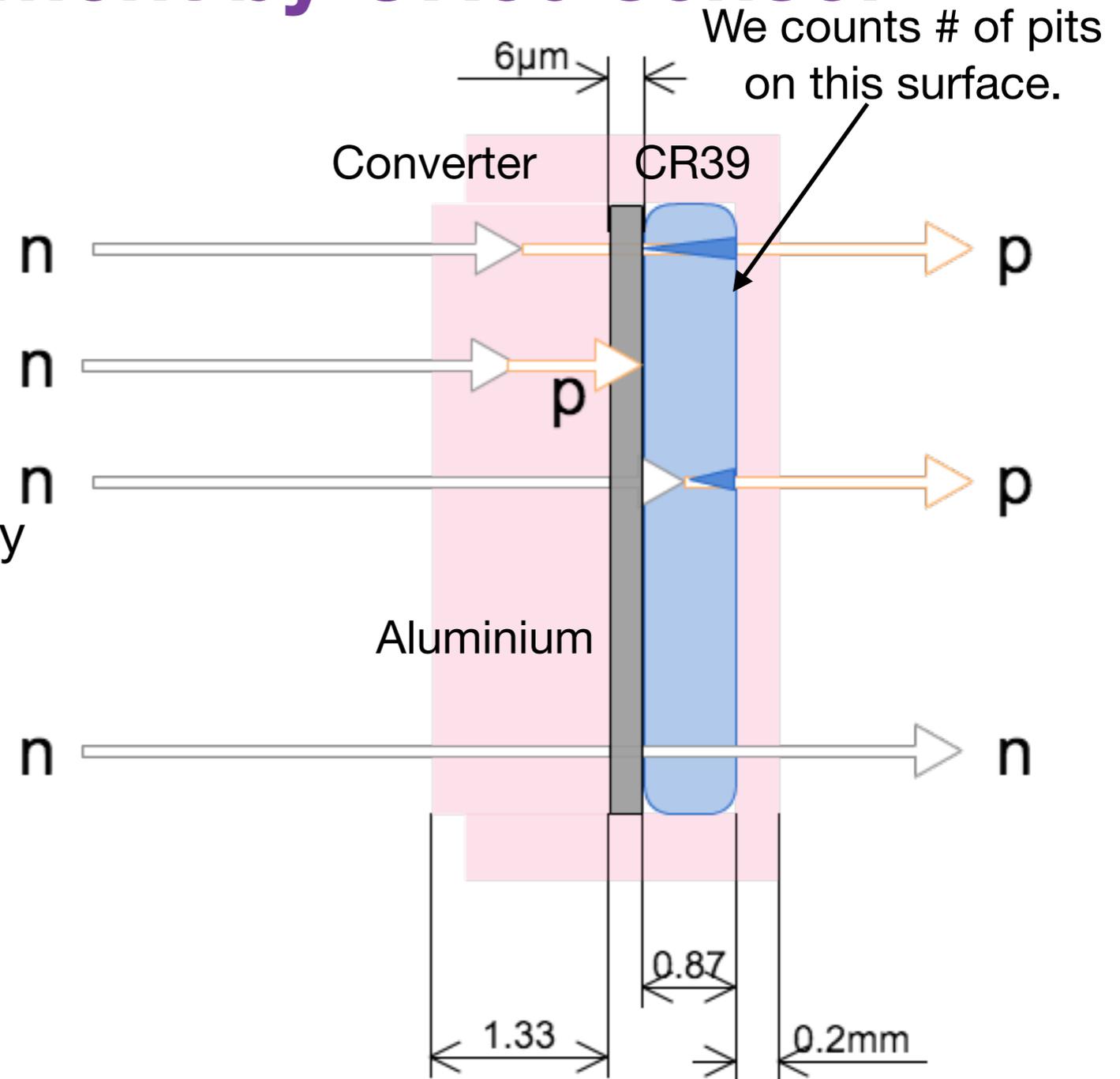
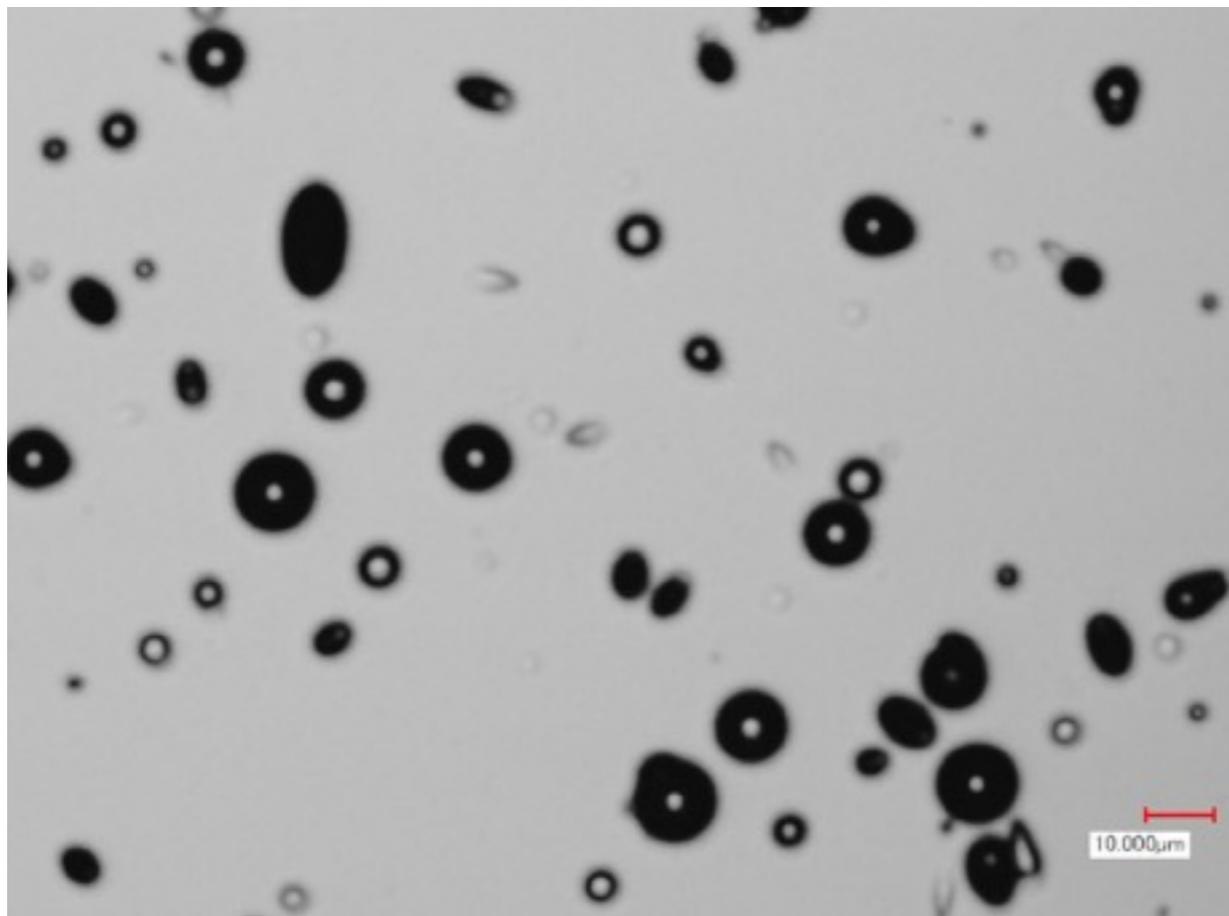
Efficiency: Eff(En) [1/n]



Calibrated by mono-energetic neutron in CYRIC(Tohoku)

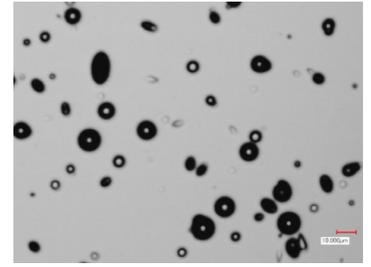
Neutron measurement by CR39 sensor

- By using different thickness of aluminium, converted protons were selected on energy threshold.
- Aluminium samples are 6, 24, 72, 204 μm .
- The pits on **CR39 sensor** are counted by eye. (9mm^2 area)

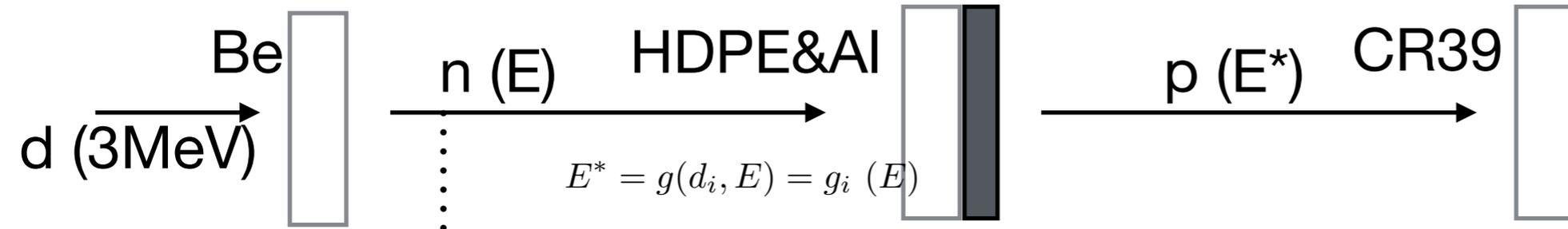


Neutron Energy Distribution

We counts # of pits on this surface.



x_i [pit/ $\mu\text{C}/\text{cm}^2$]

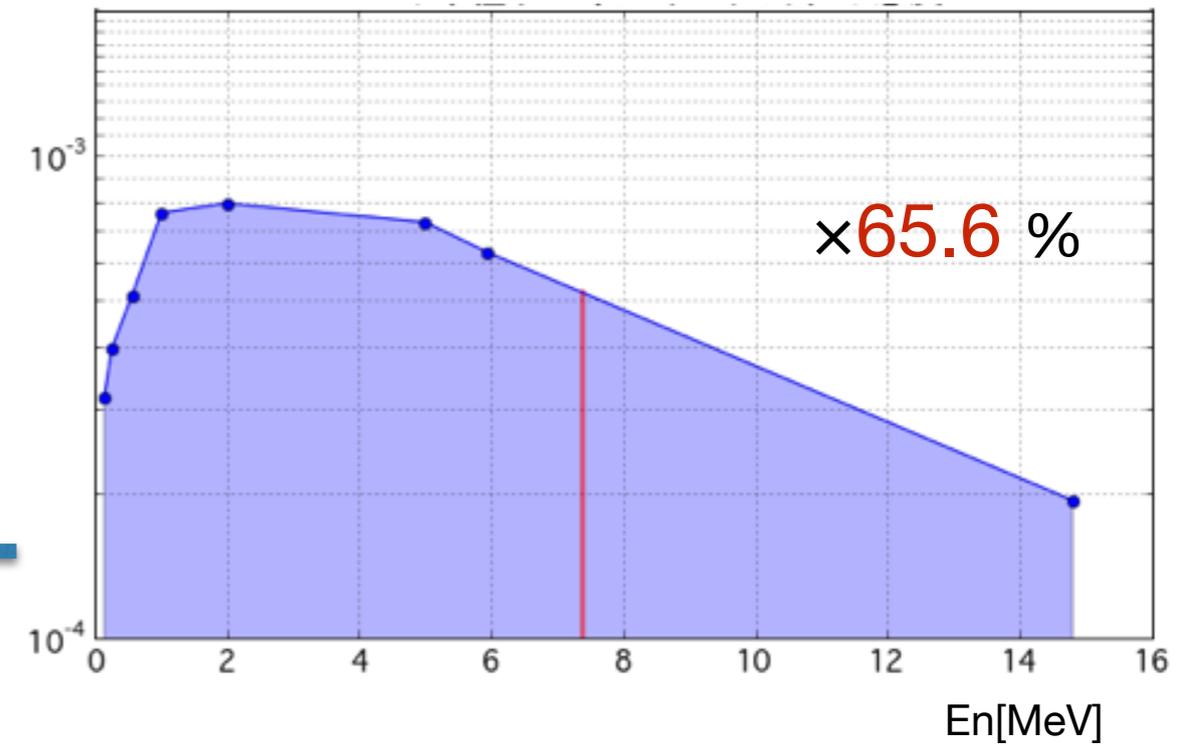
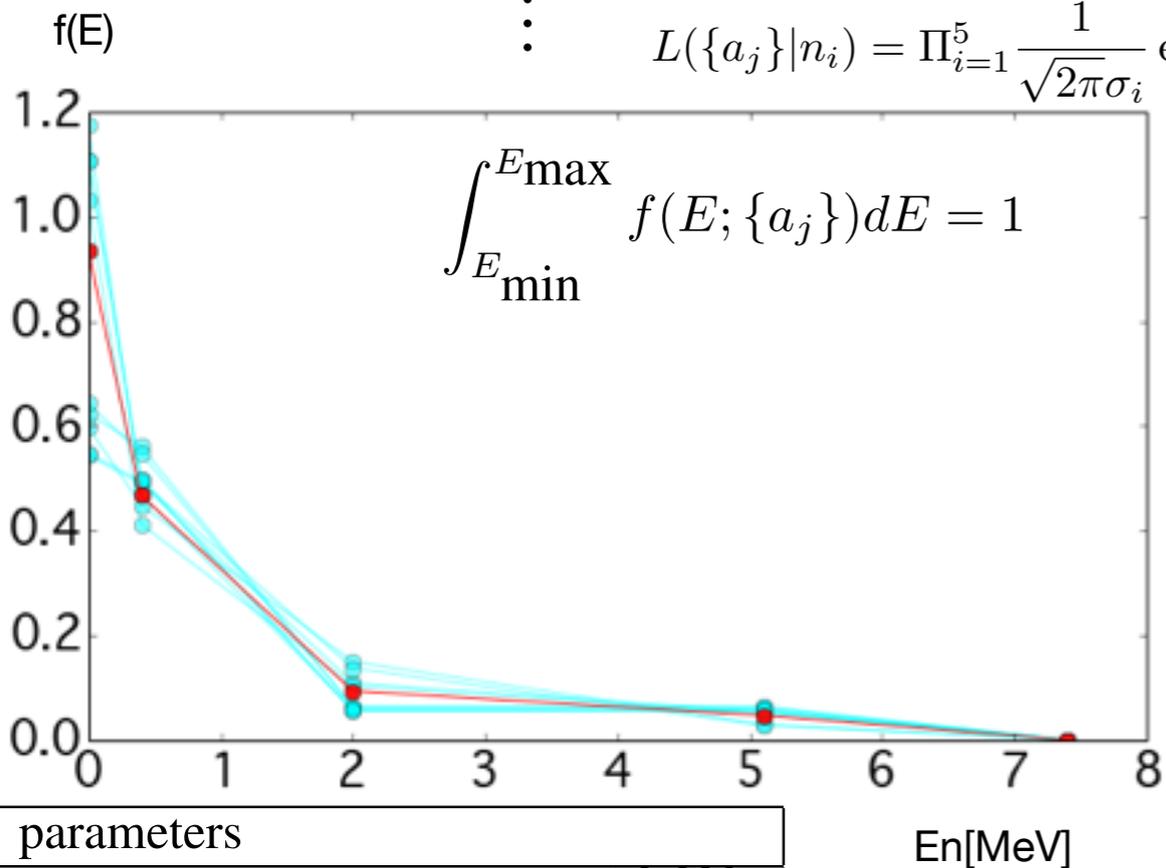


$$E^* = g(d_i, E) = g_i(E)$$

pits: $\mu_i(\{a_j\}) = \int \text{Eff}(g_i(E)) f(E; \{a_j\}) \alpha dE$

$$L(\{a_j\}|n_i) = \prod_{i=1}^5 \frac{1}{\sqrt{2\pi}\sigma_i} \exp\left[-\frac{(x_i - \mu_i)^2}{2\sigma_i^2}\right]$$

Efficiency: $\text{Eff}(E_n)$ [1/n]

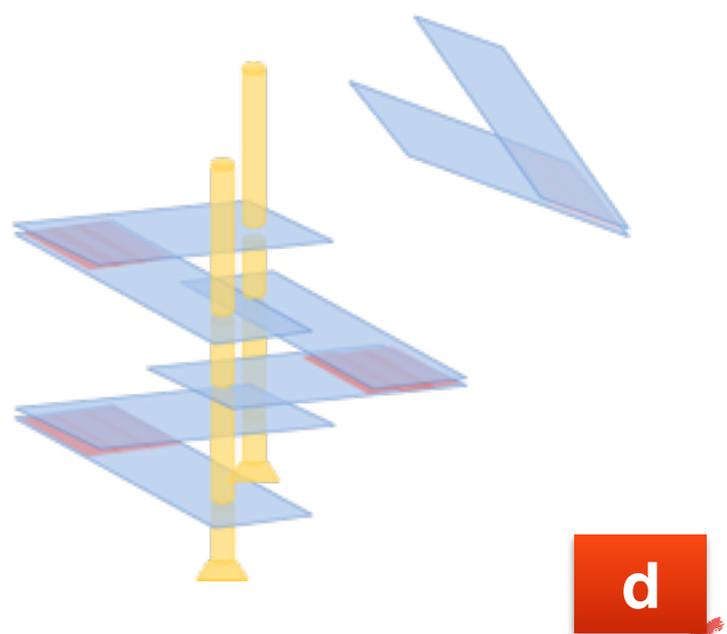


parameters	
$a_1(E = 0)$	$0.934^{+0.239}_{-0.391}$
$a_2(E = 0.4)$	$0.467^{+0.093}_{-0.055}$
$a_3(E = 2.0)$	$0.093^{+0.056}_{-0.038}$
$a_4(E = 5.1)$	$0.046^{+0.018}_{-0.019}$
$a_5(E = 7.36)$	0
α	$(1.19^{+0.12}_{-0.15}) \cdot 10^6$
χ^2	2.217

- Red line is optimised by likelihood function.
 $\chi^2/4 = 0.556$ SL = 68%
- Blue lines are satisfied with $\chi^2 = \chi^2_{\min} + 1$, which means $1\sigma_\mu$

Neutron irradiation for Glue samples

- 2 types of conductive glues(E4110, E4110LV) are targeted.
3 way of adherence are tested.
 - ▶ Recipe A: 60°C-6h (company recommended), 120µm
 - ▶ Recipe B: 40°C-24h (France groups), 120µm
 - ▶ Recipe C: 23°C-3h (company recommended), 120µm
- These samples are irradiated by around 10^{12} n(1-MeV)/cm².

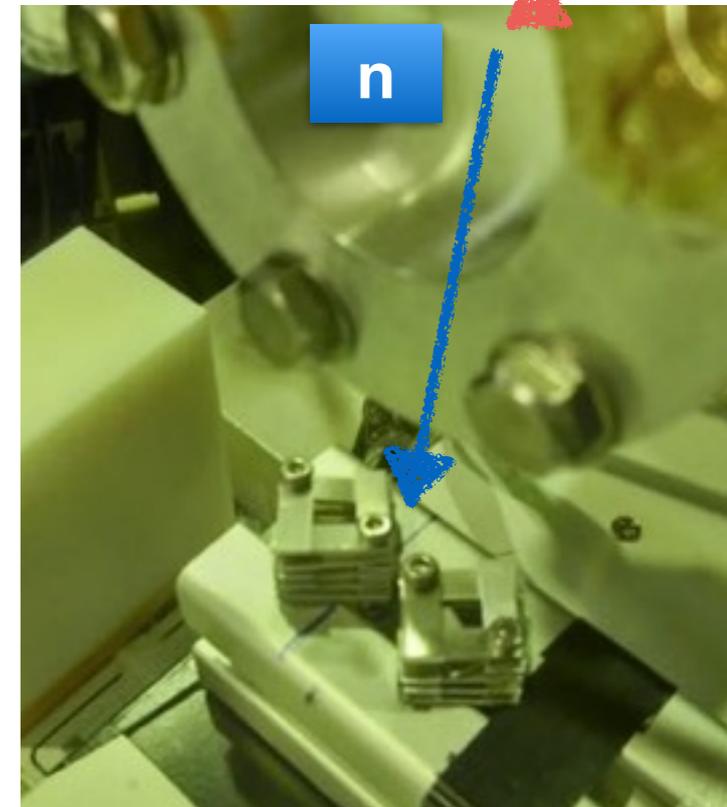


Recommended properties

	E4110	E4110-LV
23°C	×	×
40°C	✓	✓
60°C	✓	✓✓

Irradiation dose

sample	N _n n/cm ²
E4110	3.9E+09
E4110	5.3E+10
E4110	1.1E+12
E4110LV	3.9E+09
E4110LV	1.9E+11
E4110LV	1.1E+12



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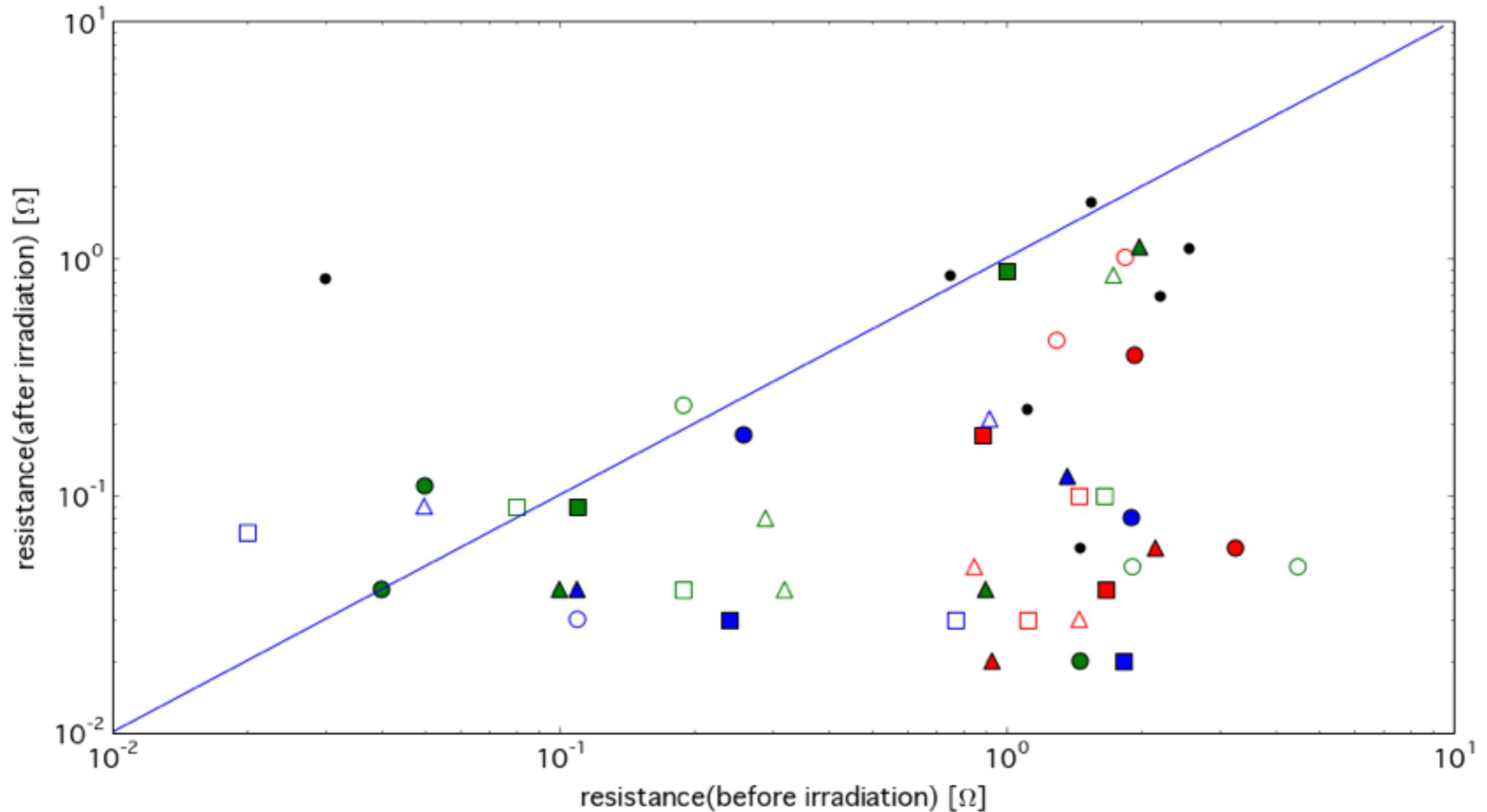
- Measurement of Radiation Damage
- Evaluation



Resistance of Glue Samples

• 23°C • 40°C • 60°C

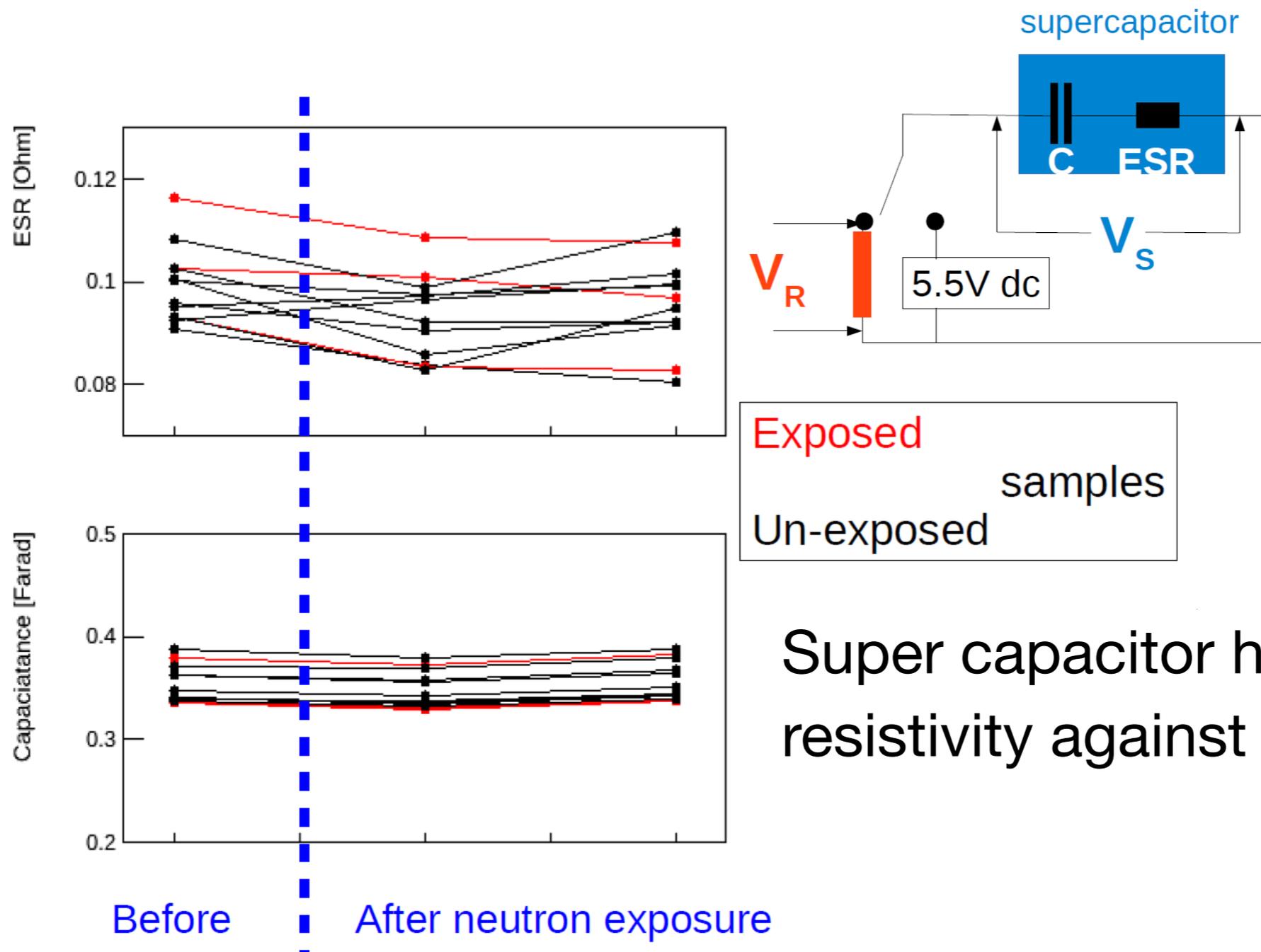
• control ○ 10^9 n/cm² △ 10^{10} n/cm² □ 10^{12} n/cm²



- couldn't understand big difference of resistance before irradiation.
- Every recipes has no sign of radiation damage up to around 10^{12} n(1-MeV)/cm².

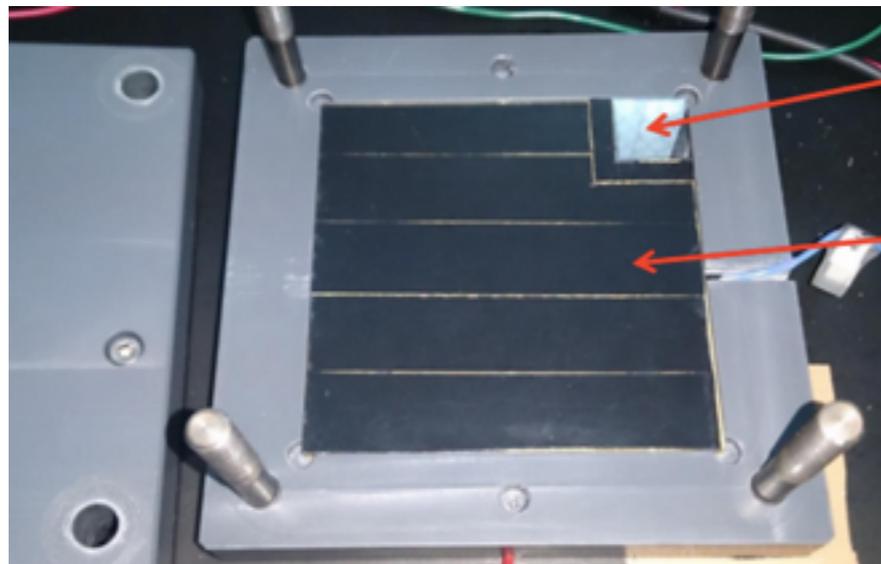
Thanks to
Kozakai-san

Super capacitor



Current-Voltage characteristics

Checked increase of dark current before and after irradiation.

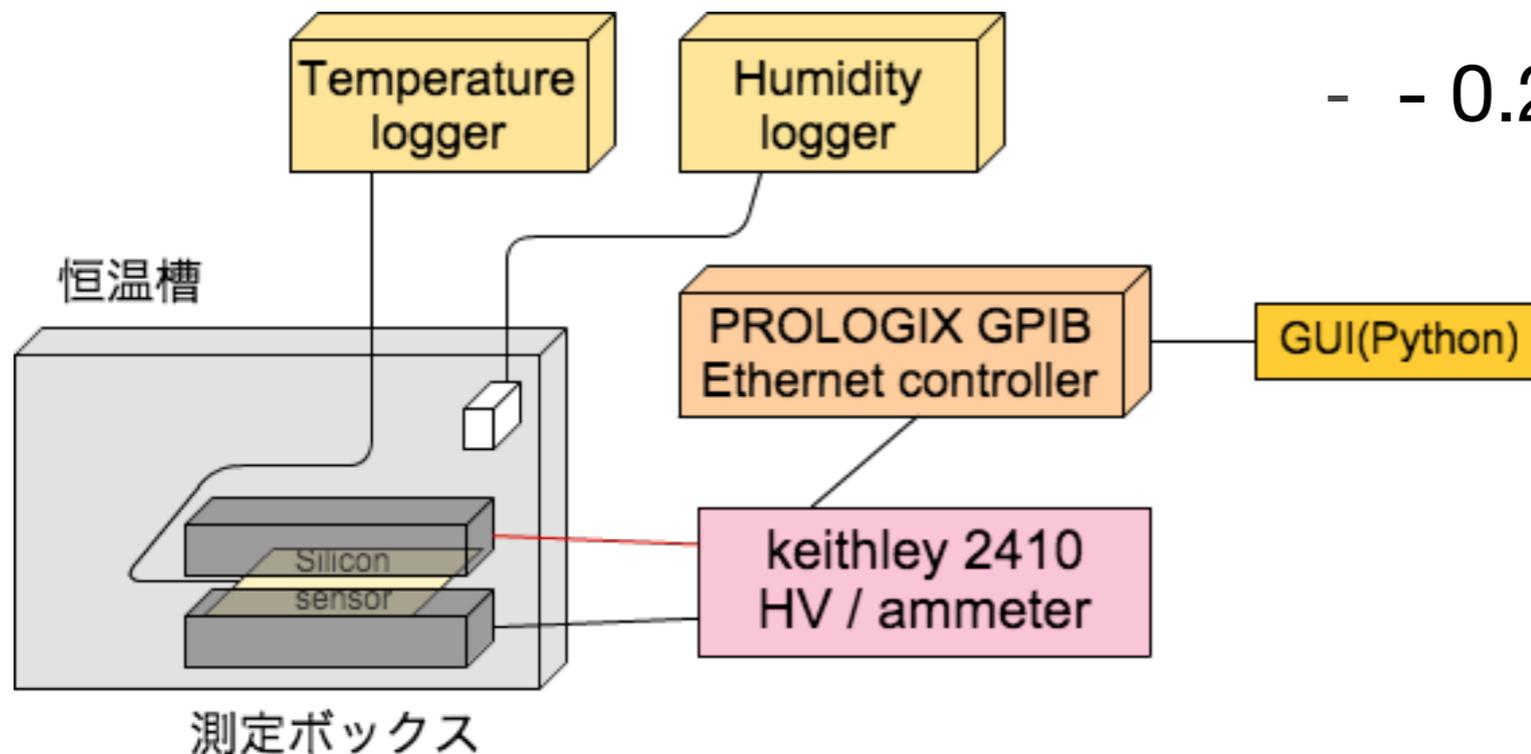


Silicon baby chip

Insulator

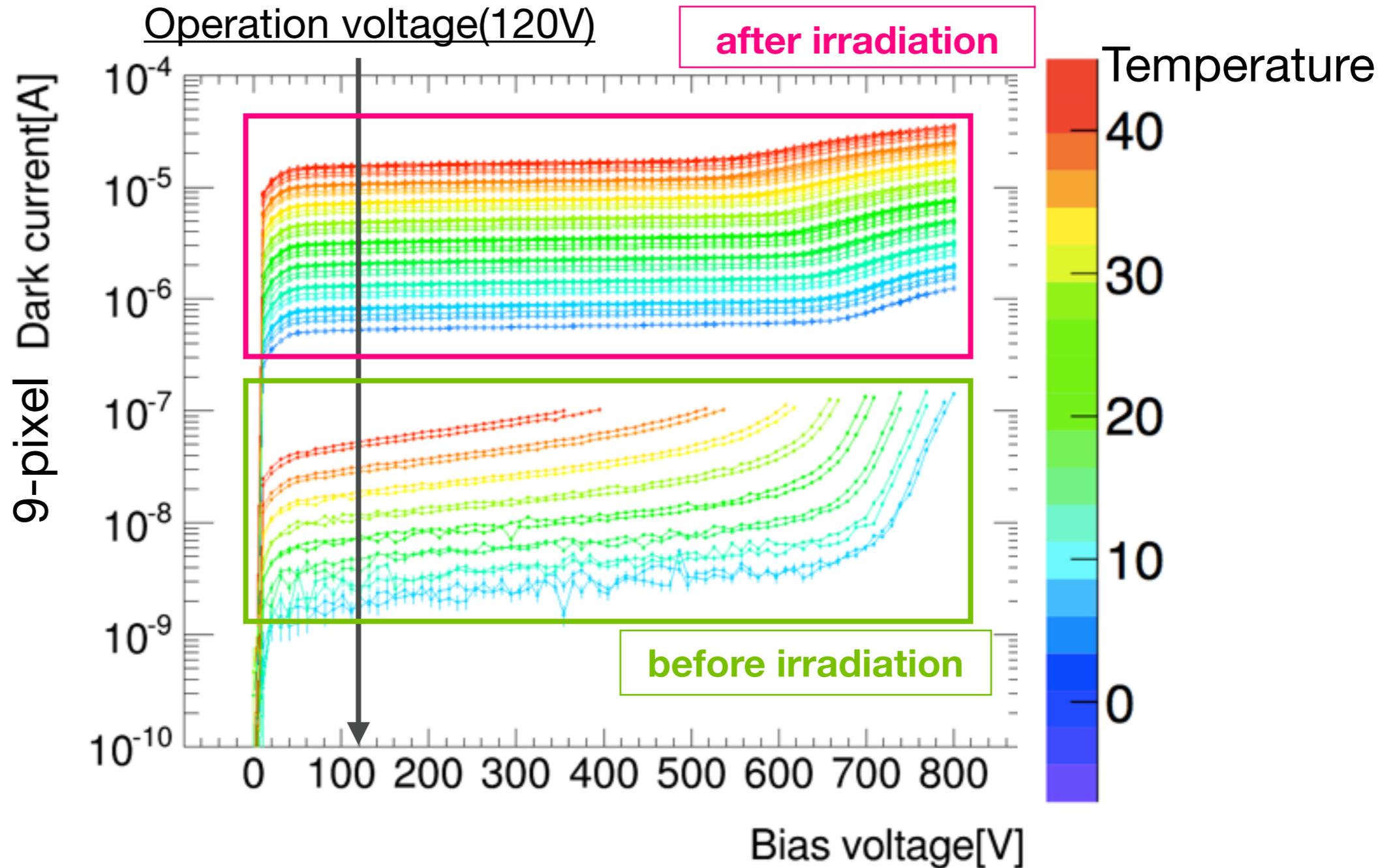
controlled voltage and temperature

- Temperature: maintainer
 - 5 °C ~ 45 °C
- Voltage: source meter
 - 0 V ~ 800 V
 - - 0.2 V ~ 0.2 V



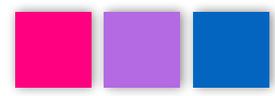
Current-Voltage characteristics

- Large increase in dark current



breakdown voltage

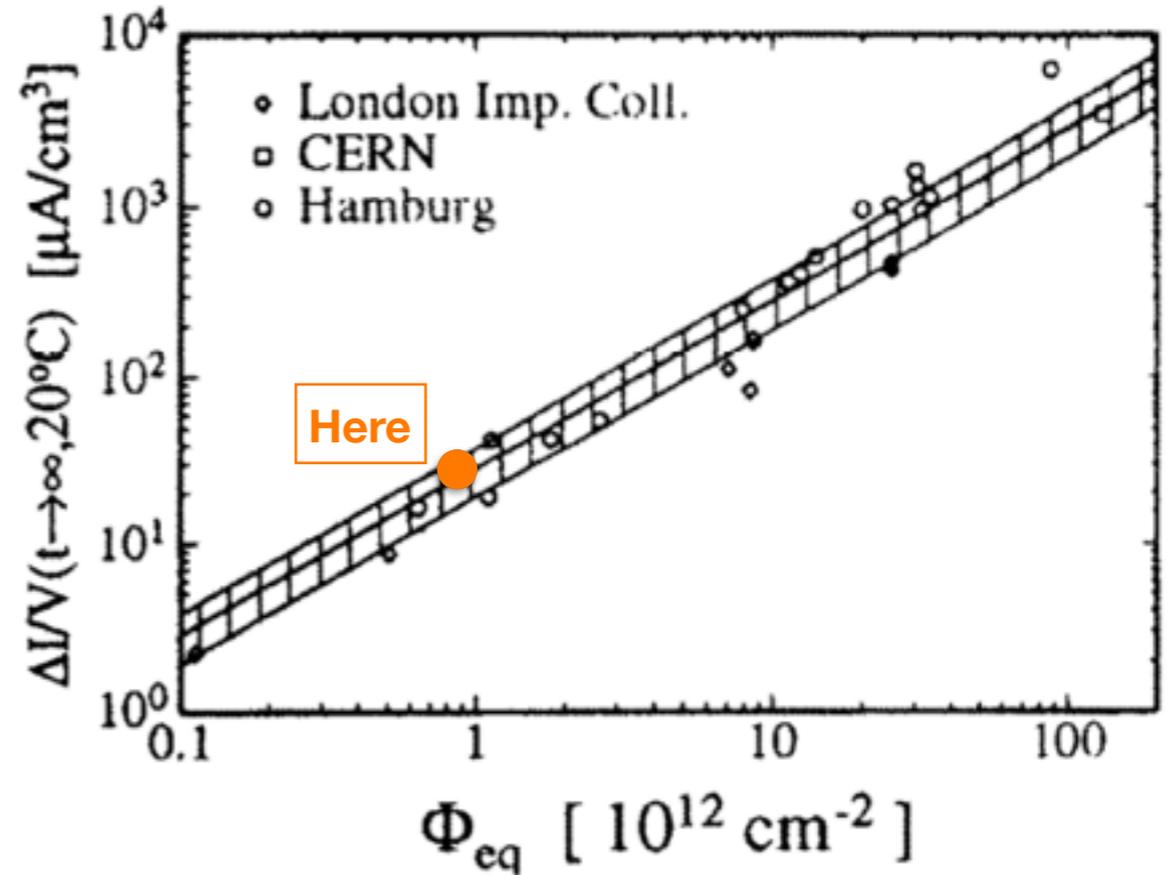
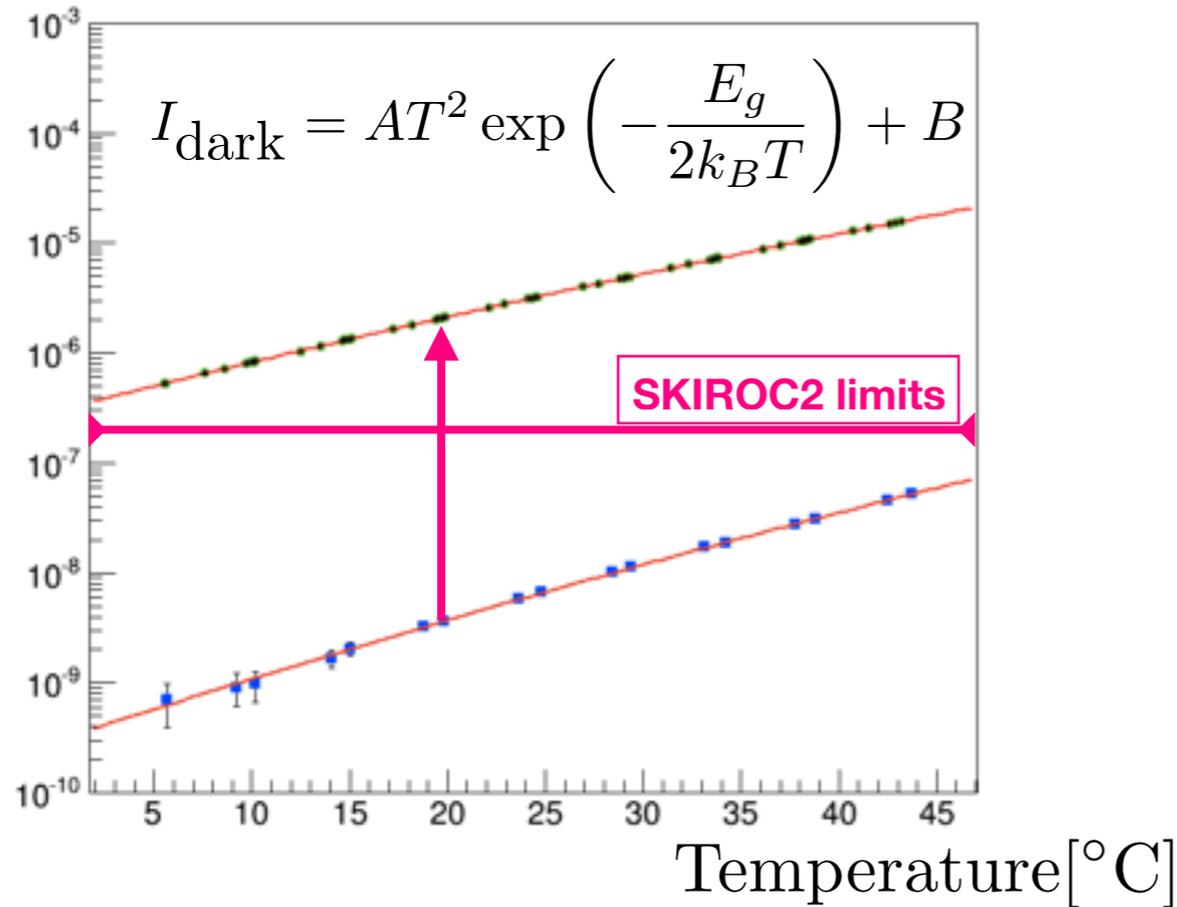
dark current @ operation voltage



Current-Temperature characteristics at 120 V

- measured temperature dependency of dark current at 120 V a long time after irradiation.

Dark Current [A]



about 2μA increase @ 20°C

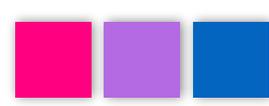
$$2\mu\text{A} / (1.5\text{cm} \times 1.5\text{cm} \times 300\mu\text{m}) = 30\mu\text{A}/\text{cm}^3$$

equivalent neutron flux is around **9.2×10¹¹ n(1-MeV)/cm²**

Conclusion

- consistent with previous experiment.
- dark current reaches SKIROC2 design limit after **30 - 60 years**.





Conclusions

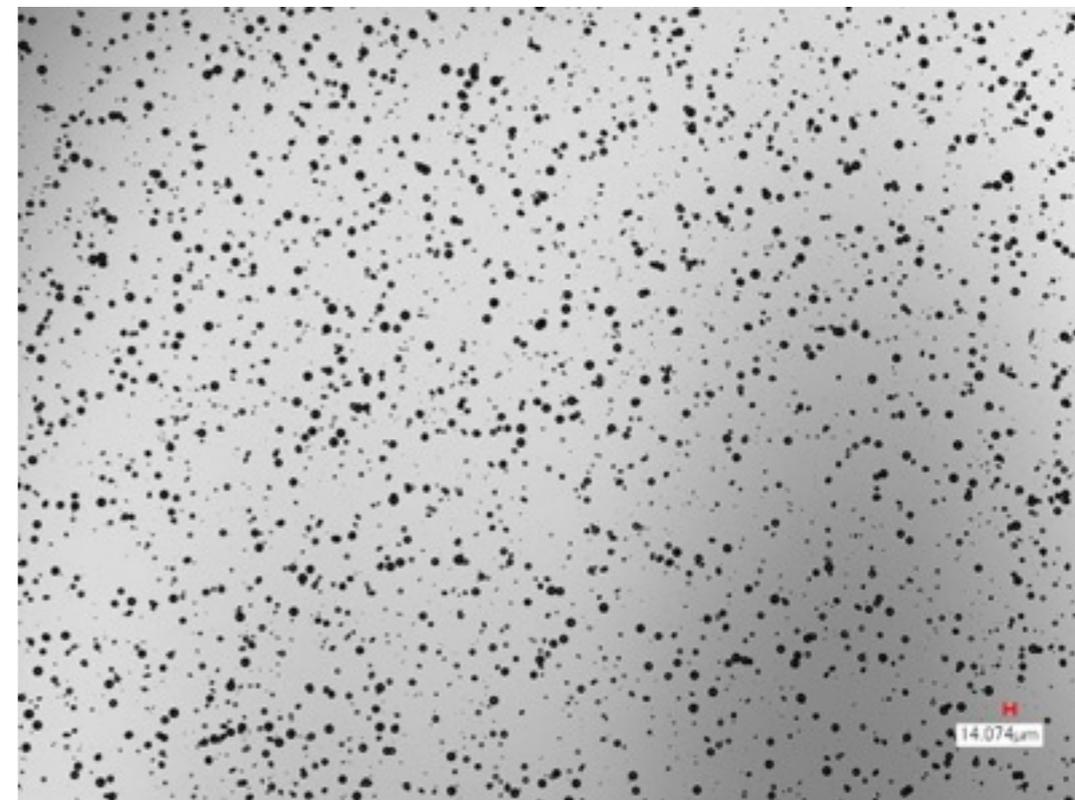
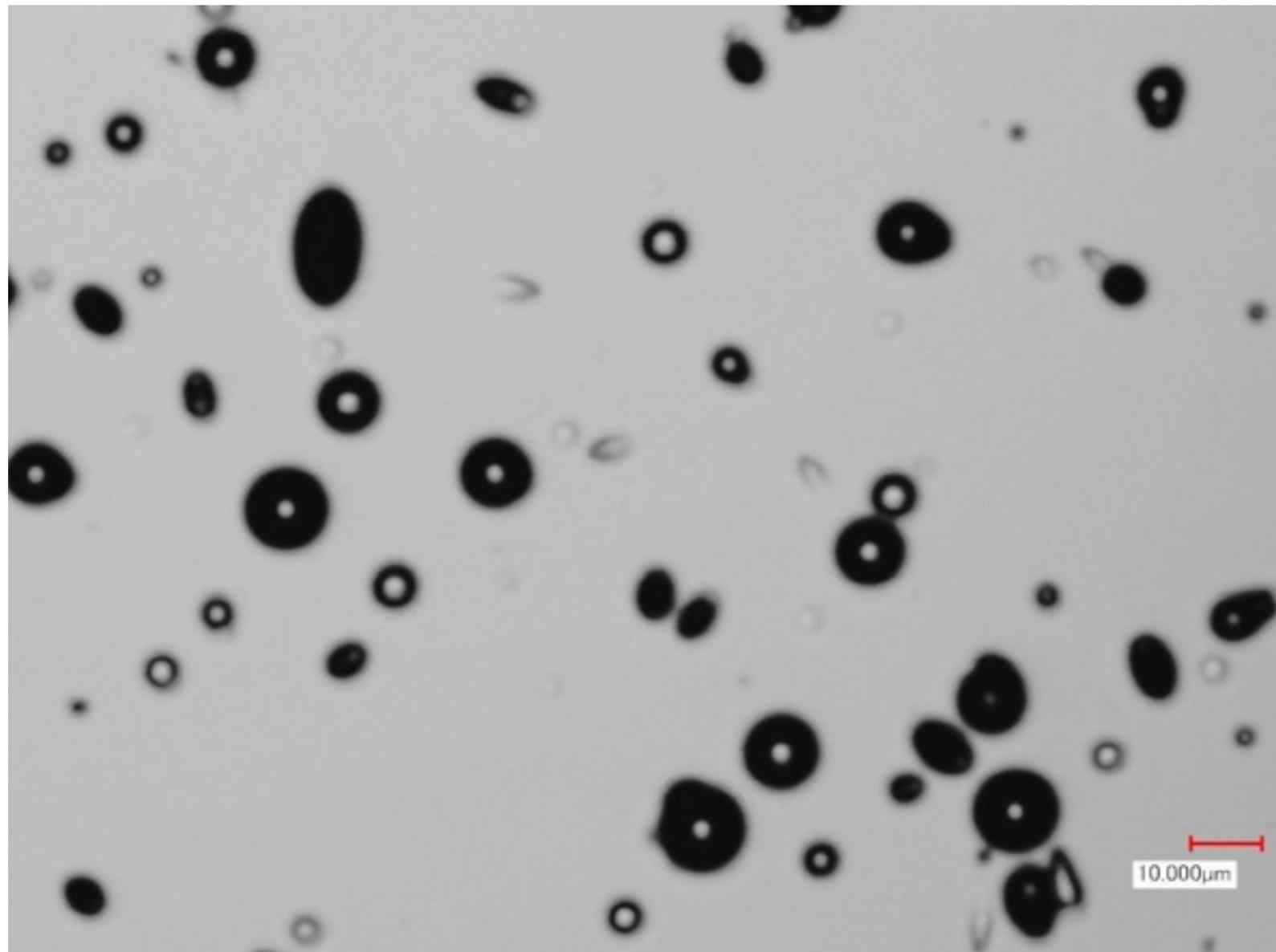
- Based on expected radiation dose on ILD ECAL, ECAL components are irradiated with neutrons.
- Neutron dose was measured using CR39 sensor. (still preliminary)
- Both **super capacitor** and **2 conductive glues** with several cooking recipes had also been tested up to around **10^{12} n(1-MeV)/cm². (100 years)**
- No significant degradation was seen for them and we can safely use them for the ILC project.
- As silicon, IV properties are significantly changed by irradiation. Our results is consistent with previous data.
- Silicon dark current expected to exceed **SKIROC2 design limit**, after **30 - 60 years of 1 TeV ILC** in inner part of ECAL endcap.

BackUp

Hitoshi Nakanishi
December 9 , 2015

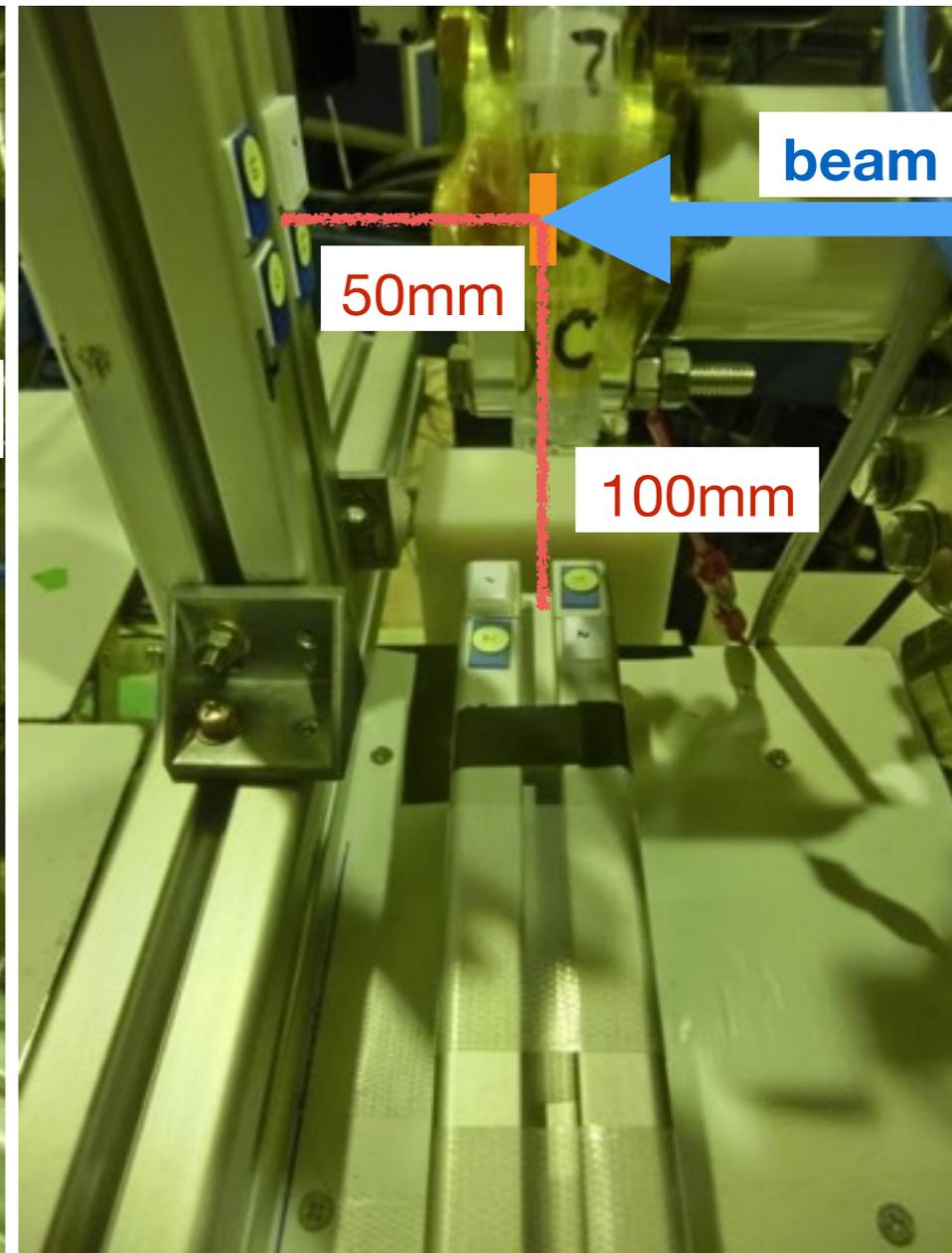
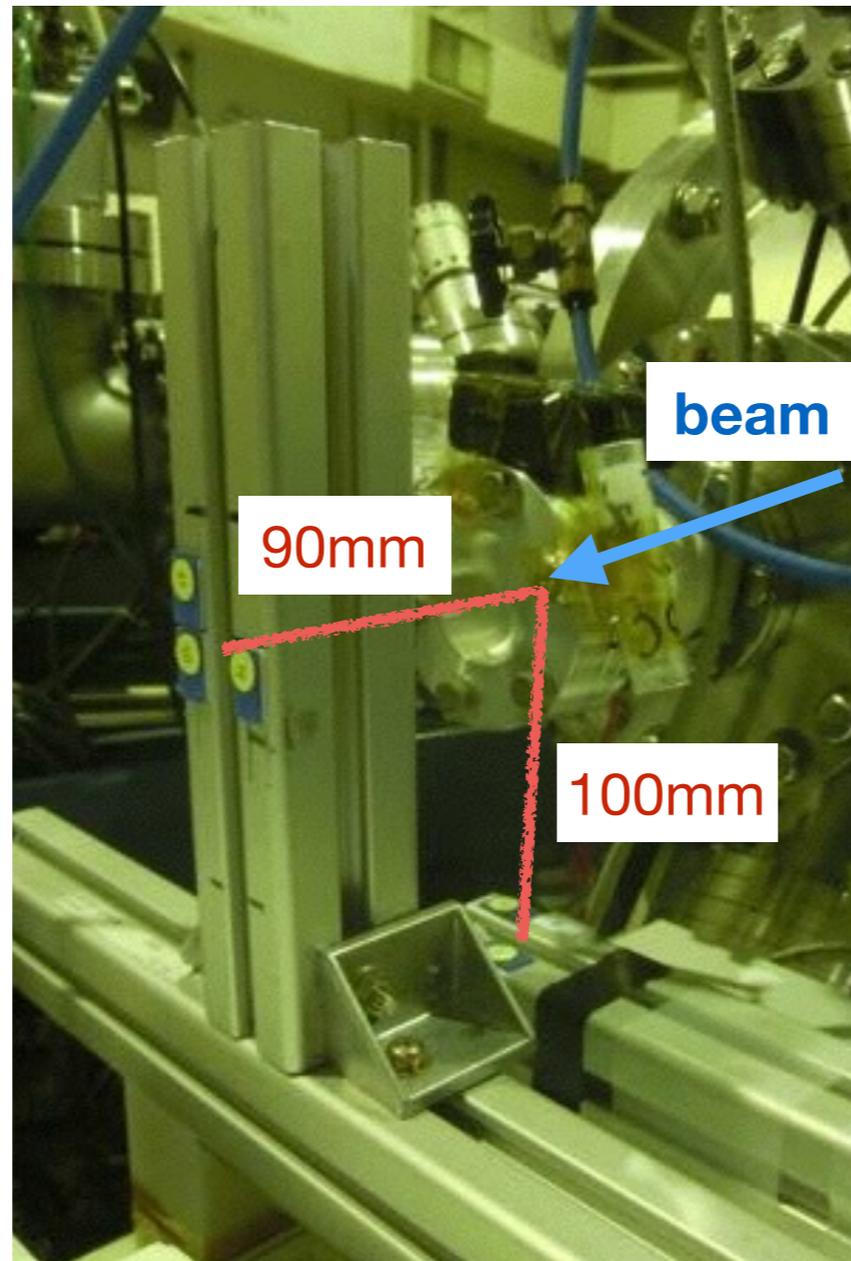
CR39 sensor pit count

- The Landaua inc. evaluated neutron counts.
 - chemical edging by NaOH 10 [mol/L] 70°C, 6h
 - pit size is extended to 10 μm .
 - The pits on **CR39 sensor** are counted by eye. (9mm² area)

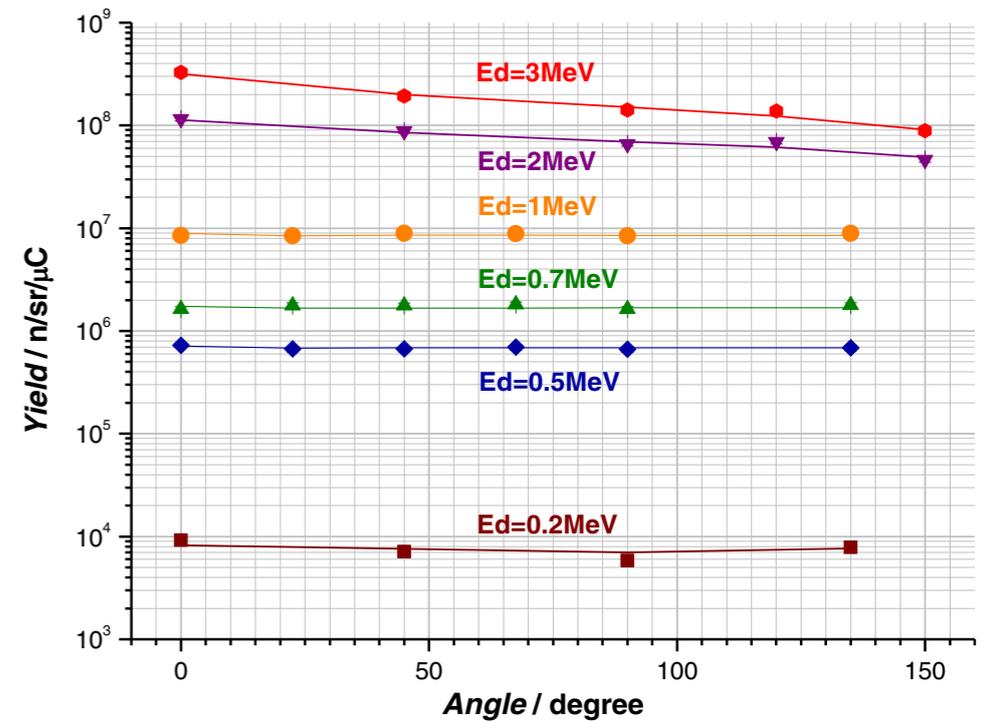
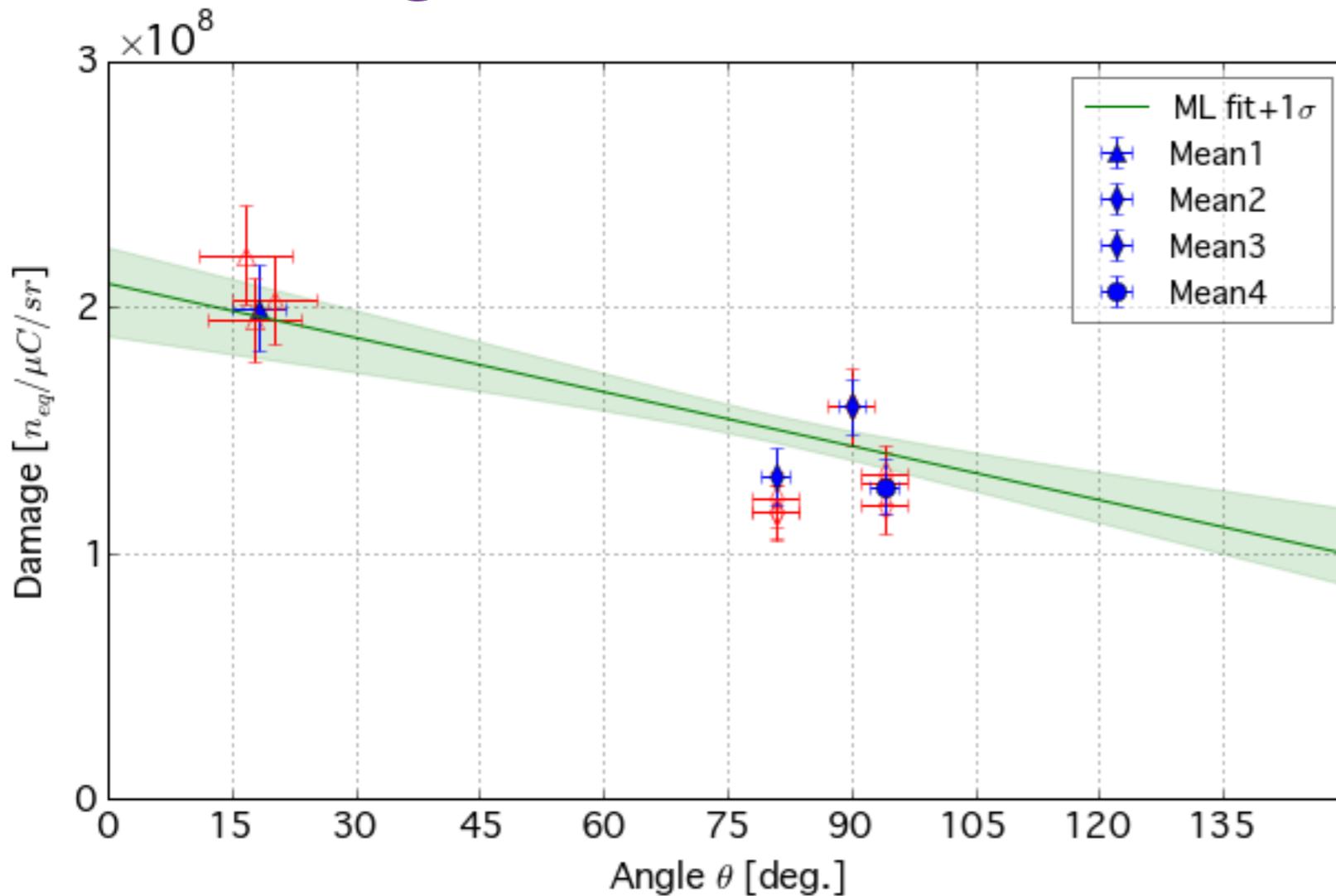


Neutron measurement by CR39 sensor

- 20 CR39 sensors
- Fixed by Aluminium frame
- Position = Irradiation position of glue samples



Angular distribution of Neutron dose

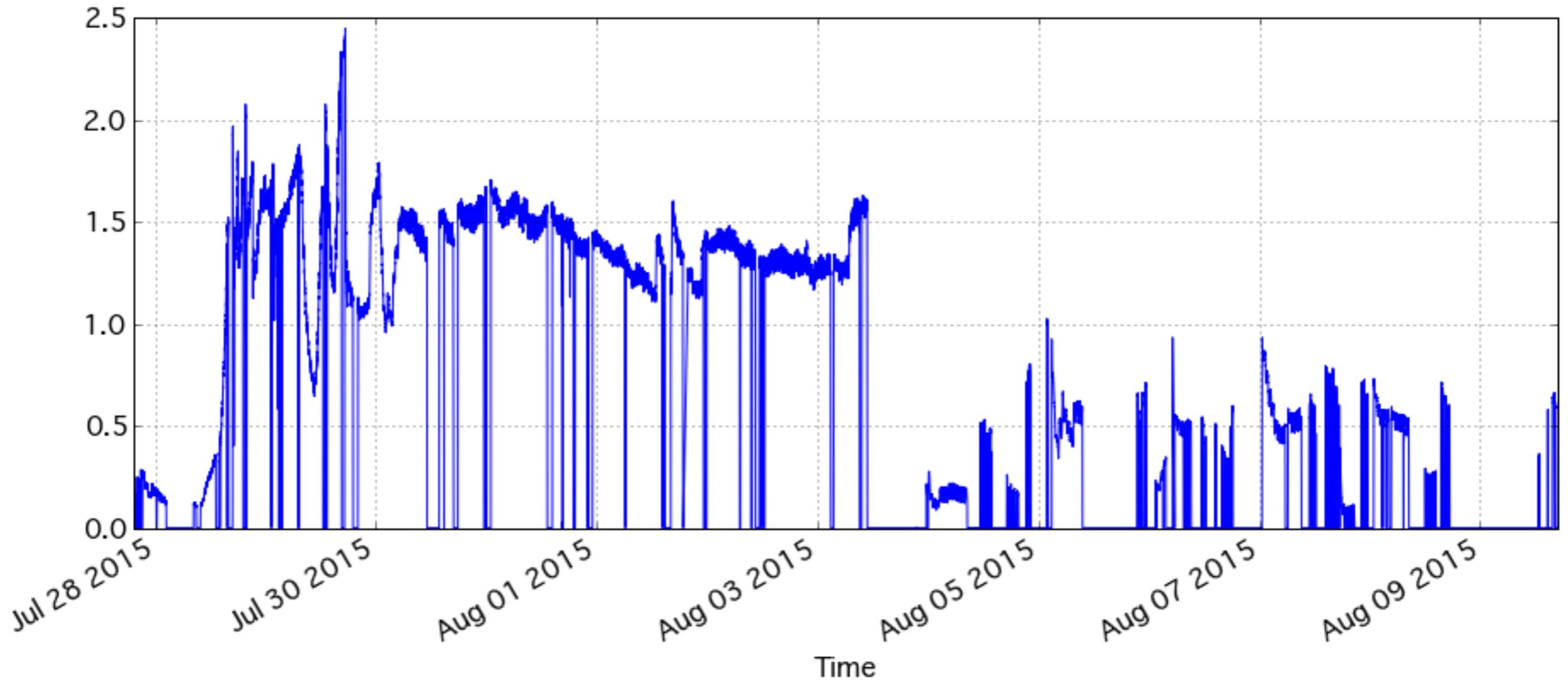


Yubin Zuo et al. / Physics Procedia 60 (2014) 220 – 227

- Red points are measured data, and blue points are mean at each position.
- Straight line are assumed.
- Green line are optimised by ML methods and green band is 1σ .
- Damage function were convoluted. $\int D(E)f(E)dE = 0.873^{+0.026}_{-0.029(stat.)} [n_{1-MeV,eq}/n]$

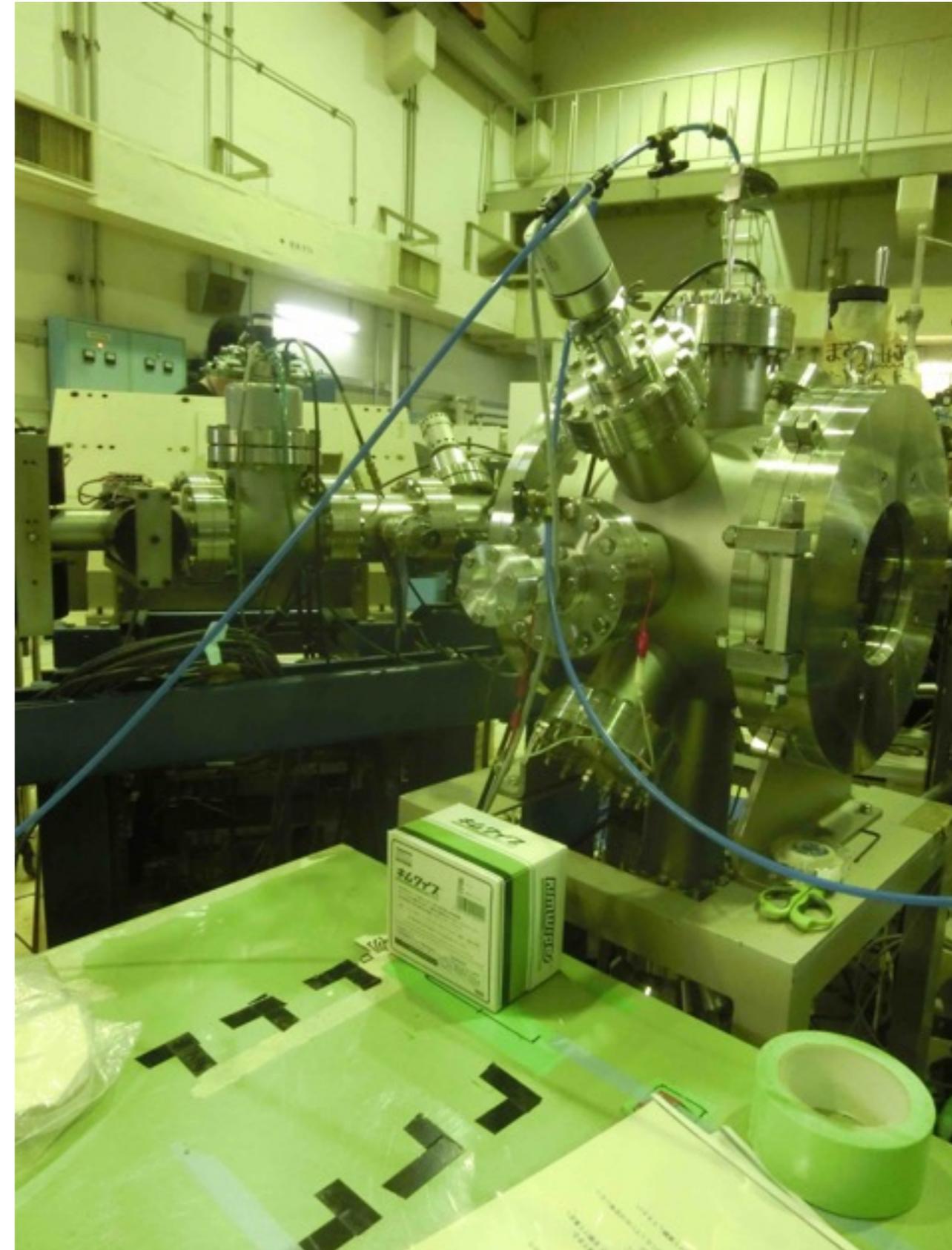
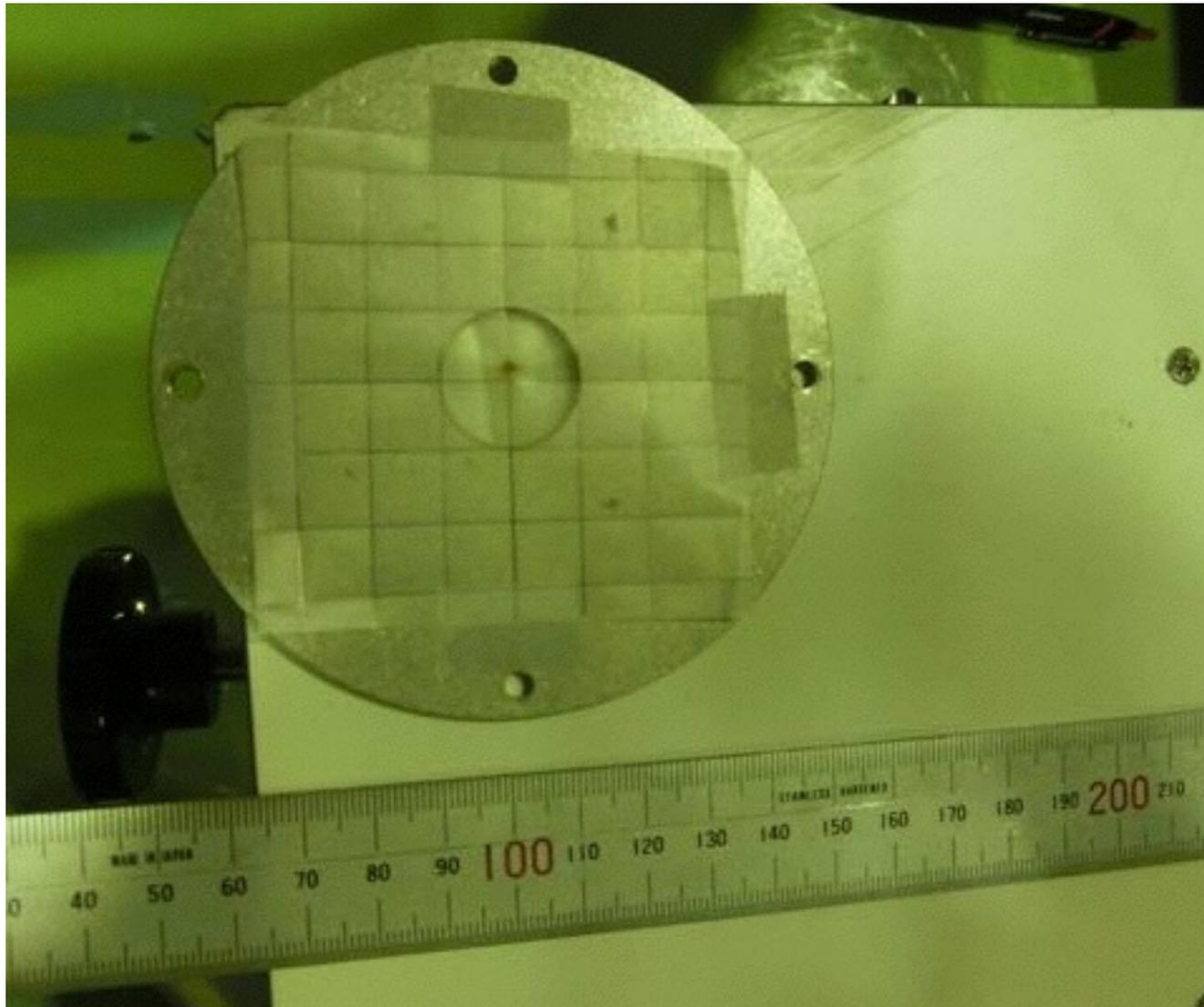
Beam Run: 7/27(Mon) ~ 8/9(Sun)

Target
Current[μA]

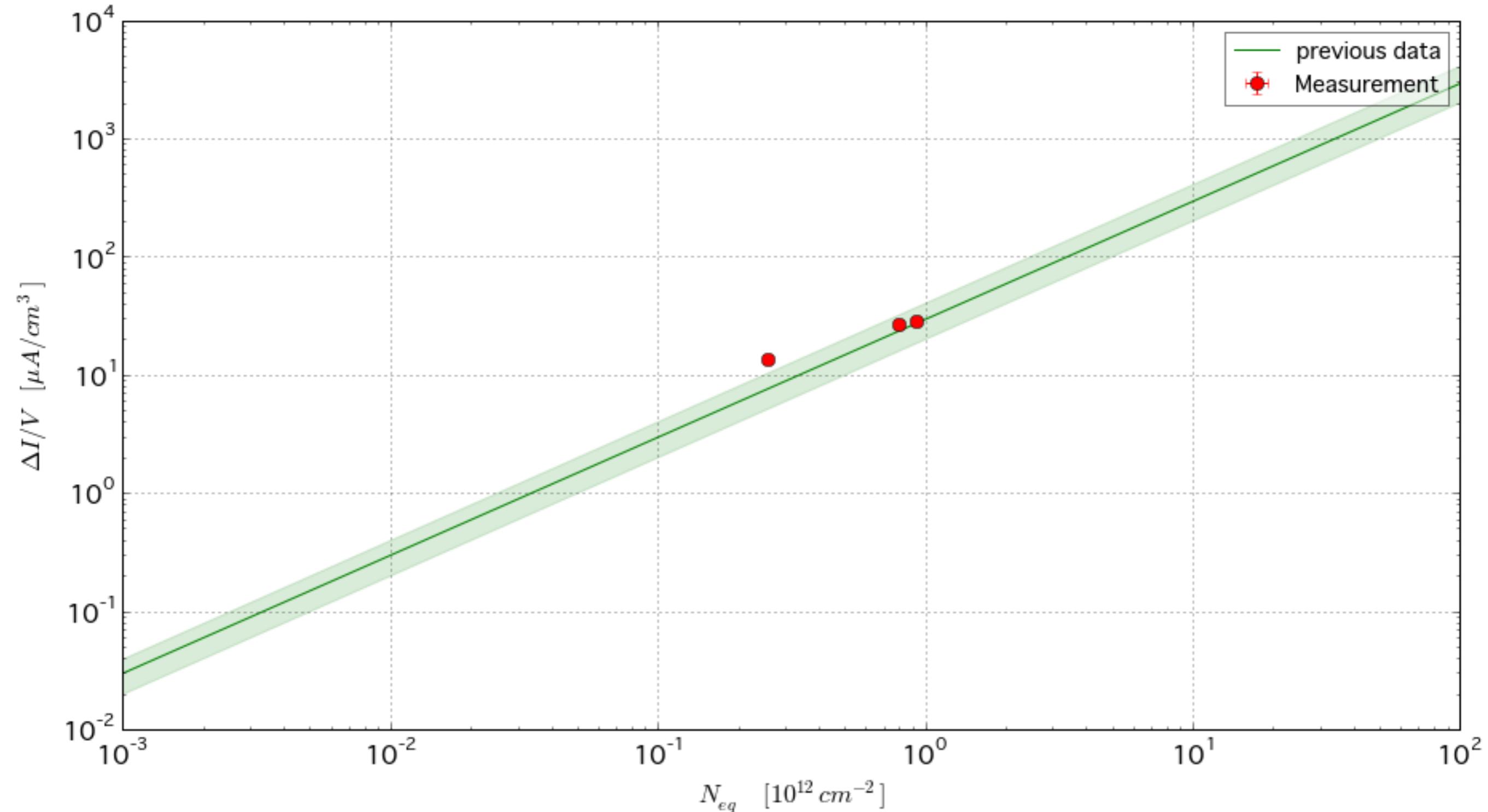


Neutron irradiation experiment (7/27)

- Be target: $\phi 20 \times 1.5$ mm
- deuteron beam:
size: < 4 mm
- beam alignment were done.



Increase of leakage current and Neutron dose



- Red points are datum of irradiated silicon.
- 3 lines are drawn from previous data.